

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				2 *****
				3 *
				4 *            Zvector E6 instruction tests for VRR-i encoded:
				5 *
				6 *            E650 VCVB        - VECTOR CONVERT TO BINARY    (32)
				7 *            E652 VCVBG       - VECTOR CONVERT TO BINARY    (64)
				8 *
				9 *            James Wekel June 2024
				10 *****
				11
				12 *****
				13 *
				14 *            basic instruction tests
				15 *
				16 *****
				17 *    This program tests proper functioning of the z/arch E6 VRR-i vector
				18 *    convert to binary instructions. Exceptions are not tested.
				19 *
				20 *    PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				21 *    obvious coding errors. None of the tests are thorough. They are
				22 *    NOT designed to test all aspects of any of the instructions.
				23 *
				24 *****
				25 *
				26 *    *Testcase zvector-e6-11-convertbinary: VECTOR E6 VRR-i instruction
				27 *    *
				28 *    *            Zvector E6 tests for VRR-i encoded instruction:
				29 *    *
				30 *    *            E650 VCVB        - VECTOR CONVERT TO BINARY    (32)
				31 *    *            E652 VCVBG       - VECTOR CONVERT TO BINARY    (64)
				32 *    *
				33 *    *    # -----
				34 *    *    #    This tests only the basic function of the instruction.
				35 *    *    #    Exceptions are NOT tested.
				36 *    *    # -----
				37 *    *
				38 *    main size        2
				39 *    numcpu           1
				40 *    sysclear
				41 *    archlvl         z/Arch
				42 *
				43 *    diag8cmd        enable    # (needed for messages to Hercules console)
				44 *    loadcore        "\$(testpath)/zvector-e6-11-convertbinary.core" 0x0
				45 *    diag8cmd        disable   # (reset back to default)
				46 *
				47 *    *Done
				48 *****
00000000		00000000	00002227	50 ZVE6TST    START 0
				51            USING ZVE6TST, R0            Low core addressability
				52
		00000140	00000000	53 SVOLDPSW EQU    ZVE6TST+X' 140'            z/Arch Supervisor call old PSW
00000000		00000000	000001A0	55            ORG    ZVE6TST+X' 1A0'            z/Architecture RESTART PSW







LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						142	*****
						143	* cc was not as expected
						144	*****
00000270	E310	0001	0082	00000270	00000001	145	CCMSG EQU *
00000276	E310	5007	0076		00000001	146	XG R1, R1
0000027C	5410	8290			00000007	147	LB R1, M3 m3 has CS bit
00000280	4780	8054			00000490	148	N R1, =F' 1' get CS (CC set) bit
					00000254	149	BZ TESTREST ignore if not set
						150	*
						151	* extract CC extracted PSW
						152	*
00000284	5810	8ED8			000010D8	153	L R1, CCPSW
00000288	8810	000C			0000000C	154	SRL R1, 12
0000028C	5410	8294			00000494	155	N R1, =XL4' 3'
00000290	4210	8EE0			000010E0	156	STC R1, CCFOUND save cc
						157	*
						158	* FILL IN MESSAGE
						159	*
00000294	4820	5004			00000004	160	LH R2, TNUM get test number and convert
00000298	4E20	8EC8			000010C8	161	CVD R2, DECNUM
0000029C	D211	8EB2	8E9C	000010B2	0000109C	162	MVC PRT3, EDIT
000002A2	DE11	8EB2	8EC8	000010B2	000010C8	163	ED PRT3, DECNUM
000002A8	D202	8E57	8EBF	00001057	000010BF	164	MVC CCPRTNUM(3), PRT3+13 fill in message with test #
						165	
000002AE	D207	8E74	500A	00001074	0000000A	166	MVC CCPRTNAME, OPNAME fill in message with instruction
						167	
000002B4	B982	0022				168	XGR R2, R2 get CC as U8
000002B8	4320	5008			00000008	169	IC R2, CC
000002BC	4E20	8EC8			000010C8	170	CVD R2, DECNUM and convert
000002C0	D211	8EB2	8E9C	000010B2	0000109C	171	MVC PRT3, EDIT
000002C6	DE11	8EB2	8EC8	000010B2	000010C8	172	ED PRT3, DECNUM
000002CC	D200	8E8A	8EC1	0000108A	000010C1	173	MVC CCPRTEXP(1), PRT3+15 fill in message with CC field
						174	
000002D2	B982	0022				175	XGR R2, R2 get CCFOUND as U8
000002D6	4320	8EE0			000010E0	176	IC R2, CCFOUND
000002DA	4E20	8EC8			000010C8	177	CVD R2, DECNUM and convert
000002DE	D211	8EB2	8E9C	000010B2	0000109C	178	MVC PRT3, EDIT
000002E4	DE11	8EB2	8EC8	000010B2	000010C8	179	ED PRT3, DECNUM
000002EA	D200	8E9A	8EC1	0000109A	000010C1	180	MVC CCPRTGOT(1), PRT3+15 fill in message with ccfound
						181	
000002F0	4100	0055			00000055	182	LA R0, CCPRTLNG message length
000002F4	4110	8E47			00001047	183	LA R1, CCPRTLNE messagfe address
000002F8	45F0	8168			00000368	184	BAL R15, RPTERROR
						185	
000002FC	47F0	814A			0000034A	186	B FAILCONT

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						188	*****
						189	* result not as expected:
						190	* issue message with test number, instruction under test
						191	* and instruction l2
						192	*****
				00000300	00000001	193	FAILMSG EQU *
00000300	4820	5004			00000004	194	LH R2, TNUM get test number and convert
00000304	4E20	8EC8			000010C8	195	CVD R2, DECNUM
00000308	D211	8EB2 8E9C		000010B2	0000109C	196	MVC PRT3, EDIT
0000030E	DE11	8EB2 8EC8		000010B2	000010C8	197	ED PRT3, DECNUM
00000314	D202	8E18 8EBF		00001018	000010BF	198	MVC PRTNUM(3), PRT3+13 fill in message with test #
						199	
0000031A	D207	8E33 500A		00001033	0000000A	200	MVC PRTNAME, OPNAME fill in message with instruction
						201	
00000320	B982	0022				202	XGR R2, R2 get M3 as U8
00000324	4320	5007			00000007	203	IC R2, M3 and convert
00000328	4E20	8EC8			000010C8	204	CVD R2, DECNUM
0000032C	D211	8EB2 8E9C		000010B2	0000109C	205	MVC PRT3, EDIT
00000332	DE11	8EB2 8EC8		000010B2	000010C8	206	ED PRT3, DECNUM
00000338	D201	8E44 8EC0		00001044	000010C0	207	MVC PRTM3(2), PRT3+14 fill in message with m3 field
						208	
0000033E	4100	003F			0000003F	209	LA R0, PRTLNG message length
00000342	4110	8E08			00001008	210	LA R1, PRTLNE messagfe address
00000346	45F0	8168			00000368	211	BAL R15, RPTERROR
						213	*****
						214	* continue after a failed test
						215	*****
				0000034A	00000001	216	FAILCONT EQU *
0000034A	5800	8290			00000490	217	L R0, =F' 1' set GLOBAL failed test indicator
0000034E	5000	8E00			00001000	218	ST R0, FAILED
						219	
00000352	41C0	C004			00000004	220	LA R12, 4(0, R12) next test address
00000356	47F0	802A			0000022A	221	B NEXTE6
						223	*****
						224	* end of testing; set ending psw
						225	*****
				0000035A	00000001	226	ENDTEST EQU *
0000035A	5810	8E00			00001000	227	L R1, FAILED did a test fail?
0000035E	1211					228	LTR R1, R1
00000360	4780	8268			00000468	229	BZ EOJ No, exit
00000364	47F0	8280			00000480	230	B FAILTEST Yes, exit with BAD PSW
						231	









LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				296	*****
				297	*            Normal completion or Abnormal termination PSWs
				298	*****
00000458	00020001 80000000			300	E0JPSW    DC        OD' 0' , X' 0002000180000000' , AD(0)
00000468	B2B2 8258		00000458	302	E0J            LPSWE E0JPSW            Normal completion
00000470	00020001 80000000			304	FAILPSW    DC        OD' 0' , X' 0002000180000000' , AD(X' BAD' )
00000480	B2B2 8270		00000470	306	FAILTEST    LPSWE FAILPSW            Abnormal termination
				308	*****
				309	*            Working Storage
				310	*****
00000484	00000000			312	CTLRO        DS        F                    CRO
00000488	00000000			313	DS        F
				314	
0000048C	00002160			315	E6TADR        DC        A(E6TESTS)            address of E6 test table
00000490				317	LTORG ,            Literals pool
00000490	00000001			318	=F' 1'
00000494	00000003			319	=XL4' 3'
00000498	0000			320	=H' 0'
0000049A	005F			321	=AL2(L' MSGMSG)
				322	
				323	*            some constants
				324	
	00000400	00000001		325	K            EQU        1024            One KB
	00001000	00000001		326	PAGE        EQU        (4*K)            Size of one page
	00010000	00000001		327	K64        EQU        (64*K)            64 KB
	00100000	00000001		328	MB        EQU        (K*K)            1 MB
				329	
				330	
	AABBCCDD	00000001		331	REG2PATT    EQU        X' AABBCCDD'            Polluted Register pattern
	000000DD	00000001		332	REG2LOW    EQU                    X' DD'            (last byte above)

LOC	OBJECT	CODE	ADDR1	ADDR2	STMT
					334 *=====
					335 *
					336 * NOTE: start data on an address that is easy to display
					337 * within Hercules
					338 *
					339 *=====
					340
0000049C			0000049C	00001000	341
					342 FAILED DC F' 0' some test failed?
00001000	00000000				343 TESTING DC F' 0' current test number
					344
					345 *****
					346 * TEST failed : result messgae
					347 *****
					348 *
					349 * failed message and associated editting
					350 *
00001008	40404040	40404040			351 PRTLNE DC C' Test # '
00001018	A7A7A7				352 PRTNUM DC C' xxx'
0000101B	40868189	93858440			353 DC C' failed for instruction '
00001033	A7A7A7A7	A7A7A7A7			354 PRTNAME DC CL8' xxxxxxxx'
0000103B	40A689A3	884094F3			355 DC C' with m3='
00001044	A7A7				356 PRTMB DC C' xx'
00001046	4B				357 DC C' . '
			0000003F	00000001	358 PRTLNG EQU *- PRTLNE
					359
					360 *****
					361 * TEST failed : CC message
					362 *****
					363 *
					364 * failed message and associated editting
					365 *
00001047	40404040	40404040			366 CCPRTLNE DC C' Test # '
00001057	A7A7A7				367 CCPRTNUM DC C' xxx'
0000105A	40A69996	95874083			368 DC c' wrong cc for instruction '
00001074	A7A7A7A7	A7A7A7A7			369 CCPRTNAME DC CL8' xxxxxxxx'
0000107C	4085A797	8583A385			370 DC C' expected: cc='
0000108A	A7				371 CCPRTEXP DC C' x'
0000108B	6B				372 DC C' , '
0000108C	40998583	8589A585			373 DC C' received: cc='
0000109A	A7				374 CCPRTGOT DC C' x'
0000109B	4B				375 DC C' . '
			00000055	00000001	376 CCPRTLNG EQU *- CCPRTLNE
					377
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LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				433 *****	
				434 * <b>Macros to help build test tables</b>	
				435 * -----	
				436 * <b>VRR_I Macro to help build test tables</b>	
				437 *****	
				438 <b>MACRO</b>	
				439 <b>VRR_I &amp;INST, &amp;MB, &amp;CC</b>	
				440 . *	&INST - VRS-d instruction under test
				441 . *	&MB - P2 (bit 0), P1 (bit 2) and
				442 . *	CS (bit 3)
				443 . *	&CC - expected CC
				444 . *	
				445 . *	note: M4 - bit 0 IOM (always 0)
				446 . *	
				447 . *	
				448       LCLA &XCC(4) &CC has mask values for FAILED condition codes	
				449 &XCC(1) SETA 7 CC != 0	
				450 &XCC(2) SETA 11 CC != 1	
				451 &XCC(3) SETA 13 CC != 2	
				452 &XCC(4) SETA 14 CC != 3	
				453	
				454       GBLA &TNUM	
				455 &TNUM SETA &TNUM+1	
				456	
				457       DS OFD	
				458       USING *, R5	base for test data and test routine
				459	
				460 T&TNUM DC A(X&TNUM)	address of test routine
				461       DC H' &TNUM	test number
				462       DC XL1' 00'	
				463       DC HL1' &MB'	&MB
				464       DC HL1' &CC'	cc
				465       DC HL1' &XCC(&CC+1)'	cc failed mask
				466	
				467       DC CL8' &INST'	instruction name
				468       DC A(16)	result length
				469 REA&TNUM DC A(RE&TNUM)	result address
				470 . *	
				471 *	INSTRUCTION UNDER TEST ROUTINE
				472 X&TNUM DS OF	
				473       LG R1, R1FUDGE	pollute R1
				474       VL V1, RE&TNUM+8	get V1 source
				475	
				476       &INST R1, V1, &MB	test instruction
				477	
				478       STG R1, R10OUTPUT	save
				479       EPSW R2, R0	exptract psw
				480       ST R2, CCPSW	to save CC
				481	
				482       BR R11	return
				483	
				484 RE&TNUM DC OF	
				485       DROP R5	
				486	
				487       MEND	

489	*****		
490	*	PTTABLE Macro to generate table of pointers to individual tests	
491	*****		
492			
493		MACRO	
494		PTTABLE	
495		GBLA	&TNUM
496		LCLA	&CUR
497	&CUR	SETA	1
498	. *		
499	TTABLE	DS	OF
500	. LOOP	ANOP	
501	. *		
502		DC	A(T&CUR) address of test
503	. *		
504	&CUR	SETA	&CUR+1
505		AIF	(&CUR LE &TNUM) . LOOP
506	*		
507		DC	A(0) END OF TABLE
508		DC	A(0)
509	. *		
510		MEND	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				512 *****	
				513 * E6 VRR_I tests	
				514 *****	
00001188		00000000	00002227	515 ZVE6TST CSECT ,	
				516 DS 0F	
				518 PRINT DATA	
				519 *	
				520 * E650 VCVB - VECTOR CONVERT TO BINARY (32)	
				521 * E652 VCVBG - VECTOR CONVERT TO BINARY (64)	
				522 *	
				523 * VRR_I instr, m3, m4	
				524 * followed by	
				525 * r1 - expected result (64 bits) (even for VCVB)	
				526 * v1 - 16 byte packed decimal source	
				527	
				528 * -----	
				529 * VCVB - VECTOR CONVERT TO BINARY (32)	
				530 * -----	
				531 * VCVB simple	
00001188				532 VRR_I VCVB, 1, 0	
00001188		00001188		533+ DS 0FD	
00001188	000011A4			534+ USING *, R5	base for test data and test routine
0000118C	0001			535+T1 DC A(X1)	address of test routine
0000118E	00			536+ DC H' 1'	test number
0000118F	01			537+ DC XL1' 00'	
00001190	00			538+ DC HL1' 1'	&MB
00001191	07			539+ DC HL1' 0'	cc
00001192	E5C3E5C2 40404040			540+ DC HL1' 7'	cc failed mask
0000119C	00000010			541+ DC CL8' VCVB'	instruction name
000011A0	000011C8			542+ DC A(16)	result length
				543+REA1 DC A(RE1)	result address
				544+*	INSTRUCTION UNDER TEST ROUTINE
000011A4				545+X1 DS 0F	
000011A4	E310 8EE8 0004		000010E8	546+ LG R1, R1FUDGE	pollute R1
000011AA	E710 5048 0006		000011D0	547+ VL V1, RE1+8	get V1 source
000011B0	E611 0010 0050			548+ VCVB R1, V1, 1	test instruction
000011B6	E310 8F20 0024		00001120	549+ STG R1, R10UTPUT	save
000011BC	B98D 0020			550+ EPSW R2, R0	exptract psw
000011C0	5020 8ED8		000010D8	551+ ST R2, CCPSW	to save CC
000011C4	07FB			552+ BR R11	return
000011C8				553+RE1 DC 0F	
000011C8				554+ DROP R5	
000011C8	AABBCCDD 0000000A			555 DC XL08' AABBCCDD0000000A'	R1 result
000011D0	00000000 00000000			556 DC XL16' 0000000000000000000000000000000010C'	V1 source
000011D8	00000000 0000010C				
				557	
				558 VRR_I VCVB, 1, 0	
000011E0				559+ DS 0FD	
000011E0		000011E0		560+ USING *, R5	base for test data and test routine
000011E0	000011FC			561+T2 DC A(X2)	address of test routine
000011E4	0002			562+ DC H' 2'	test number
000011E6	00			563+ DC XL1' 00'	
000011E7	01			564+ DC HL1' 1'	&MB
000011E8	00			565+ DC HL1' 0'	cc





LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000012A4	00000010			620+	DC	A(16)	result length
000012A8	000012D0			621+REA4	DC	A(RE4)	result address
				622+*			INSTRUCTION UNDER TEST ROUTINE
000012AC				623+X4	DS	OF	
000012AC	E310 8EE8 0004		000010E8	624+	LG	R1, R1FUDGE	pollute R1
000012B2	E710 5048 0006		000012D8	625+	VL	V1, RE4+8	get V1 source
000012B8	E611 0010 0050			626+	VCVB	R1, V1, 1	test instruction
000012BE	E310 8F20 0024		00001120	627+	STG	R1, R10UTPUT	save
000012C4	B98D 0020			628+	EPSW	R2, R0	exptract psw
000012C8	5020 8ED8		000010D8	629+	ST	R2, CCPSW	to save CC
000012CC	07FB			630+	BR	R11	return
000012D0				631+RE4	DC	OF	
000012D0				632+	DROP	R5	
000012D0	AABBCCDD FFF75EA0			633	DC	XL08' AABBCCDDFFF75EA0'	R1 result
000012D8	00000000 00000000			634	DC	XL16' 0000000000000000000000000565600D'	V1 source
000012E0	00000000 0565600D			635			
				636	VRR_I	VCVB, 1, 0	INT_MAX
000012E8				637+	DS	OFD	
000012E8		000012E8		638+	USING	*, R5	base for test data and test routine
000012E8	00001304			639+T5	DC	A(X5)	address of test routine
000012EC	0005			640+	DC	H' 5'	test number
000012EE	00			641+	DC	XL1' 00'	
000012EF	01			642+	DC	HL1' 1'	&MB
000012F0	00			643+	DC	HL1' 0'	cc
000012F1	07			644+	DC	HL1' 7'	cc failed mask
000012F2	E5C3E5C2 40404040			645+	DC	CL8' VCVB'	instruction name
000012FC	00000010			646+	DC	A(16)	result length
00001300	00001328			647+REA5	DC	A(RE5)	result address
				648+*			INSTRUCTION UNDER TEST ROUTINE
00001304				649+X5	DS	OF	
00001304	E310 8EE8 0004		000010E8	650+	LG	R1, R1FUDGE	pollute R1
0000130A	E710 5048 0006		00001330	651+	VL	V1, RE5+8	get V1 source
00001310	E611 0010 0050			652+	VCVB	R1, V1, 1	test instruction
00001316	E310 8F20 0024		00001120	653+	STG	R1, R10UTPUT	save
0000131C	B98D 0020			654+	EPSW	R2, R0	exptract psw
00001320	5020 8ED8		000010D8	655+	ST	R2, CCPSW	to save CC
00001324	07FB			656+	BR	R11	return
00001328				657+RE5	DC	OF	
00001328				658+	DROP	R5	
00001328	AABBCCDD 7FFFFFFF			659	DC	XL08' AABBCCDD7FFFFFFF'	R1 result
00001330	00000000 00000000			660	DC	XL16' 000000000000000000000002147483647C'	V1 source
00001338	00000214 7483647C			661			
				662	VRR_I	VCVB, 1, 0	INT_MIN
00001340				663+	DS	OFD	
00001340		00001340		664+	USING	*, R5	base for test data and test routine
00001340	0000135C			665+T6	DC	A(X6)	address of test routine
00001344	0006			666+	DC	H' 6'	test number
00001346	00			667+	DC	XL1' 00'	
00001347	01			668+	DC	HL1' 1'	&MB
00001348	00			669+	DC	HL1' 0'	cc
00001349	07			670+	DC	HL1' 7'	cc failed mask
0000134A	E5C3E5C2 40404040			671+	DC	CL8' VCVB'	instruction name
00001354	00000010			672+	DC	A(16)	result length
00001358	00001380			673+REA6	DC	A(RE6)	result address

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				674+*		INSTRUCTION UNDER TEST ROUTINE	
0000135C				675+X6	DS	0F	
0000135C	E310 8EE8 0004		000010E8	676+	LG	R1, R1FUDGE	pollute R1
00001362	E710 5048 0006		00001388	677+	VL	V1, RE6+8	get V1 source
00001368	E611 0010 0050			678+	VCVB	R1, V1, 1	test instruction
0000136E	E310 8F20 0024		00001120	679+	STG	R1, R10UTPUT	save
00001374	B98D 0020			680+	EPSW	R2, R0	exptract psw
00001378	5020 8ED8		000010D8	681+	ST	R2, CCPSW	to save CC
0000137C	07FB			682+	BR	R11	return
00001380				683+RE6	DC	0F	
00001380				684+	DROP	R5	
00001380	AABBCCDD 80000000			685	DC	XL08' AABBCCDD80000000'	R1 result
00001388	00000000 00000000			686	DC	XL16' 000000000000000000000002147483648D'	V1 source
00001390	00000214 7483648D						
				687			
				688	VRR_I	VCVB, 3, 0	UINT_MAX
00001398				689+	DS	0FD	
00001398		00001398		690+	USING	*, R5	base for test data and test routine
00001398	000013B4			691+T7	DC	A(X7)	address of test routine
0000139C	0007			692+	DC	H' 7'	test number
0000139E	00			693+	DC	XL1' 00'	
0000139F	03			694+	DC	HL1' 3'	&MB
000013A0	00			695+	DC	HL1' 0'	cc
000013A1	07			696+	DC	HL1' 7'	cc failed mask
000013A2	E5C3E5C2 40404040			697+	DC	CL8' VCVB'	instruction name
000013AC	00000010			698+	DC	A(16)	result length
000013B0	000013D8			699+REA7	DC	A(RE7)	result address
				700+*			INSTRUCTION UNDER TEST ROUTINE
000013B4				701+X7	DS	0F	
000013B4	E310 8EE8 0004		000010E8	702+	LG	R1, R1FUDGE	pollute R1
000013BA	E710 5048 0006		000013E0	703+	VL	V1, RE7+8	get V1 source
000013C0	E611 0030 0050			704+	VCVB	R1, V1, 3	test instruction
000013C6	E310 8F20 0024		00001120	705+	STG	R1, R10UTPUT	save
000013CC	B98D 0020			706+	EPSW	R2, R0	exptract psw
000013D0	5020 8ED8		000010D8	707+	ST	R2, CCPSW	to save CC
000013D4	07FB			708+	BR	R11	return
000013D8				709+RE7	DC	0F	
000013D8				710+	DROP	R5	
000013D8	AABBCCDD FFFFFFFF			711	DC	XL08' AABBCCDDFFFFFFF'	R1 result
000013E0	00000000 00000000			712	DC	XL16' 00000000000000000000004294967295C'	V1 source
000013E8	00000429 4967295C						
				713			
				714	VRR_I	VCVB, 3, 3	UINT_MAX +1
000013F0				715+	DS	0FD	
000013F0		000013F0		716+	USING	*, R5	base for test data and test routine
000013F0	0000140C			717+T8	DC	A(X8)	address of test routine
000013F4	0008			718+	DC	H' 8'	test number
000013F6	00			719+	DC	XL1' 00'	
000013F7	03			720+	DC	HL1' 3'	&MB
000013F8	03			721+	DC	HL1' 3'	cc
000013F9	0E			722+	DC	HL1' 14'	cc failed mask
000013FA	E5C3E5C2 40404040			723+	DC	CL8' VCVB'	instruction name
00001404	00000010			724+	DC	A(16)	result length
00001408	00001430			725+REA8	DC	A(RE8)	result address
				726+*			INSTRUCTION UNDER TEST ROUTINE
0000140C				727+X8	DS	0F	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000140C	E310 8EE8 0004		000010E8	728+	LG	R1, R1FUDGE	pollute R1
00001412	E710 5048 0006		00001438	729+	VL	V1, RE8+8	get V1 source
00001418	E611 0030 0050			730+	VCVB	R1, V1, 3	test instruction
0000141E	E310 8F20 0024		00001120	731+	STG	R1, R10UTPUT	save
00001424	B98D 0020			732+	EPSW	R2, R0	exptract psw
00001428	5020 8ED8		000010D8	733+	ST	R2, CCPSW	to save CC
0000142C	07FB			734+	BR	R11	return
00001430				735+RE8	DC	0F	
00001430				736+	DROP	R5	
00001430	AABBCCDD 00000000			737	DC	XL08' AABBCCDD00000000'	R1 result
00001438	00000000 00000000			738	DC	XL16' 00000000000000000000000004294967296C'	V1 source
00001440	00000429 4967296C						
				739			
				740	VRR_I	VCVB, 1, 3	
00001448				741+	DS	0FD	
00001448		00001448		742+	USING	*, R5	base for test data and test routine
00001448	00001464			743+T9	DC	A(X9)	address of test routine
0000144C	0009			744+	DC	H' 9'	test number
0000144E	00			745+	DC	XL1' 00'	
0000144F	01			746+	DC	HL1' 1'	&MB
00001450	03			747+	DC	HL1' 3'	cc
00001451	0E			748+	DC	HL1' 14'	cc failed mask
00001452	E5C3E5C2 40404040			749+	DC	CL8' VCVB'	instruction name
0000145C	00000010			750+	DC	A(16)	result length
00001460	00001488			751+REA9	DC	A(RE9)	result address
				752+*			INSTRUCTION UNDER TEST ROUTINE
00001464				753+X9	DS	0F	
00001464	E310 8EE8 0004		000010E8	754+	LG	R1, R1FUDGE	pollute R1
0000146A	E710 5048 0006		00001490	755+	VL	V1, RE9+8	get V1 source
00001470	E611 0010 0050			756+	VCVB	R1, V1, 1	test instruction
00001476	E310 8F20 0024		00001120	757+	STG	R1, R10UTPUT	save
0000147C	B98D 0020			758+	EPSW	R2, R0	exptract psw
00001480	5020 8ED8		000010D8	759+	ST	R2, CCPSW	to save CC
00001484	07FB			760+	BR	R11	return
00001488				761+RE9	DC	0F	
00001488				762+	DROP	R5	
00001488	AABBCCDD DF8E1660			763	DC	XL08' AABBCCDDDF8E1660'	R1 result
00001490	00000000 00000000			764	DC	XL16' 00000000000000000000000012340565600C'	V1 source
00001498	00001234 0565600C						
				765			
				766 * VCVB simple:	p2=1		
				767	VRR_I	VCVB, 9, 0	
000014A0				768+	DS	0FD	
000014A0		000014A0		769+	USING	*, R5	base for test data and test routine
000014A0	000014BC			770+T10	DC	A(X10)	address of test routine
000014A4	000A			771+	DC	H' 10'	test number
000014A6	00			772+	DC	XL1' 00'	
000014A7	09			773+	DC	HL1' 9'	&MB
000014A8	00			774+	DC	HL1' 0'	cc
000014A9	07			775+	DC	HL1' 7'	cc failed mask
000014AA	E5C3E5C2 40404040			776+	DC	CL8' VCVB'	instruction name
000014B4	00000010			777+	DC	A(16)	result length
000014B8	000014E0			778+REA10	DC	A(RE10)	result address
				779+*			INSTRUCTION UNDER TEST ROUTINE
000014BC				780+X10	DS	0F	
000014BC	E310 8EE8 0004		000010E8	781+	LG	R1, R1FUDGE	pollute R1



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000014C2	E710 5048 0006		000014E8	782+	VL	V1, RE10+8	get V1 source
000014C8	E611 0090 0050			783+	VCVB	R1, V1, 9	test instruction
000014CE	E310 8F20 0024		00001120	784+	STG	R1, R10UTPUT	save
000014D4	B98D 0020			785+	EPSW	R2, R0	exptract psw
000014D8	5020 8ED8		000010D8	786+	ST	R2, CCPSW	to save CC
000014DC	07FB			787+	BR	R11	return
000014E0				788+RE10	DC	0F	
000014E0				789+	DROP	R5	
000014E0	AABBCCDD 0000000A			790	DC	XL08' AABBCCDD0000000A'	R1 result
000014E8	00000000 00000000			791	DC	XL16' 0000000000000000000000000000000010C'	V1 source
000014F0	00000000 0000010C						
				792			
				793	VRR_I	VCVB, 9, 0	
000014F8				794+	DS	0FD	
000014F8		000014F8		795+	USING	*, R5	base for test data and test routine
000014F8	00001514			796+T11	DC	A(X11)	address of test routine
000014FC	000B			797+	DC	H' 11'	test number
000014FE	00			798+	DC	XL1' 00'	
000014FF	09			799+	DC	HL1' 9'	&MB
00001500	00			800+	DC	HL1' 0'	cc
00001501	07			801+	DC	HL1' 7'	cc failed mask
00001502	E5C3E5C2 40404040			802+	DC	CL8' VCVB'	instruction name
0000150C	00000010			803+	DC	A(16)	result length
00001510	00001538			804+REA11	DC	A(RE11)	result address
				805+*			INSTRUCTION UNDER TEST ROUTINE
00001514				806+X11	DS	0F	
00001514	E310 8EE8 0004		000010E8	807+	LG	R1, R1FUDGE	pollute R1
0000151A	E710 5048 0006		00001540	808+	VL	V1, RE11+8	get V1 source
00001520	E611 0090 0050			809+	VCVB	R1, V1, 9	test instruction
00001526	E310 8F20 0024		00001120	810+	STG	R1, R10UTPUT	save
0000152C	B98D 0020			811+	EPSW	R2, R0	exptract psw
00001530	5020 8ED8		000010D8	812+	ST	R2, CCPSW	to save CC
00001534	07FB			813+	BR	R11	return
00001538				814+RE11	DC	0F	
00001538				815+	DROP	R5	
00001538	AABBCCDD 0000000A			816	DC	XL08' AABBCCDD0000000A'	R1 result
00001540	00000000 00000000			817	DC	XL16' 0000000000000000000000000000000010D'	V1 source
00001548	00000000 0000010D						
				818			
				819	VRR_I	VCVB, 9, 0	
00001550				820+	DS	0FD	
00001550		00001550		821+	USING	*, R5	base for test data and test routine
00001550	0000156C			822+T12	DC	A(X12)	address of test routine
00001554	000C			823+	DC	H' 12'	test number
00001556	00			824+	DC	XL1' 00'	
00001557	09			825+	DC	HL1' 9'	&MB
00001558	00			826+	DC	HL1' 0'	cc
00001559	07			827+	DC	HL1' 7'	cc failed mask
0000155A	E5C3E5C2 40404040			828+	DC	CL8' VCVB'	instruction name
00001564	00000010			829+	DC	A(16)	result length
00001568	00001590			830+REA12	DC	A(RE12)	result address
				831+*			INSTRUCTION UNDER TEST ROUTINE
0000156C				832+X12	DS	0F	
0000156C	E310 8EE8 0004		000010E8	833+	LG	R1, R1FUDGE	pollute R1
00001572	E710 5048 0006		00001598	834+	VL	V1, RE12+8	get V1 source
00001578	E611 0090 0050			835+	VCVB	R1, V1, 9	test instruction

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000157E	E310 8F20 0024		00001120	836+	STG	R1, R10OUTPUT	save
00001584	B98D 0020			837+	EPSW	R2, R0	exptract psw
00001588	5020 8ED8		000010D8	838+	ST	R2, CCPSW	to save CC
0000158C	07FB			839+	BR	R11	return
00001590				840+RE12	DC	OF	
00001590				841+	DROP	R5	
00001590	AABBCCDD 0008A160			842	DC	XL08' AABBCCDD0008A160'	R1 result
00001598	00000000 00000000			843	DC	XL16' 0000000000000000000000000565600C'	V1 source
000015A0	00000000 0565600C						
				844			
				845	VRR_I	VCVB, 9, 0	
000015A8				846+	DS	OFD	
000015A8		000015A8		847+	USING	*, R5	base for test data and test routine
000015A8	000015C4			848+T13	DC	A(X13)	address of test routine
000015AC	000D			849+	DC	H' 13'	test number
000015AE	00			850+	DC	XL1' 00'	
000015AF	09			851+	DC	HL1' 9'	&MB
000015B0	00			852+	DC	HL1' 0'	cc
000015B1	07			853+	DC	HL1' 7'	cc failed mask
000015B2	E5C3E5C2 40404040			854+	DC	CL8' VCVB'	instruction name
000015BC	00000010			855+	DC	A(16)	result length
000015C0	000015E8			856+REA13	DC	A(RE13)	result address
				857+*			INSTRUCTION UNDER TEST ROUTINE
000015C4				858+X13	DS	OF	
000015C4	E310 8EE8 0004		000010E8	859+	LG	R1, R1FUDGE	pollute R1
000015CA	E710 5048 0006		000015F0	860+	VL	V1, RE13+8	get V1 source
000015D0	E611 0090 0050			861+	VCVB	R1, V1, 9	test instruction
000015D6	E310 8F20 0024		00001120	862+	STG	R1, R10OUTPUT	save
000015DC	B98D 0020			863+	EPSW	R2, R0	exptract psw
000015E0	5020 8ED8		000010D8	864+	ST	R2, CCPSW	to save CC
000015E4	07FB			865+	BR	R11	return
000015E8				866+RE13	DC	OF	
000015E8				867+	DROP	R5	
000015E8	AABBCCDD 0008A160			868	DC	XL08' AABBCCDD0008A160'	R1 result
000015F0	00000000 00000000			869	DC	XL16' 0000000000000000000000000565600D'	V1 source
000015F8	00000000 0565600D						
				870			
				871	VRR_I	VCVB, 9, 0	INT_MAX
00001600				872+	DS	OFD	
00001600		00001600		873+	USING	*, R5	base for test data and test routine
00001600	0000161C			874+T14	DC	A(X14)	address of test routine
00001604	000E			875+	DC	H' 14'	test number
00001606	00			876+	DC	XL1' 00'	
00001607	09			877+	DC	HL1' 9'	&MB
00001608	00			878+	DC	HL1' 0'	cc
00001609	07			879+	DC	HL1' 7'	cc failed mask
0000160A	E5C3E5C2 40404040			880+	DC	CL8' VCVB'	instruction name
00001614	00000010			881+	DC	A(16)	result length
00001618	00001640			882+REA14	DC	A(RE14)	result address
				883+*			INSTRUCTION UNDER TEST ROUTINE
0000161C				884+X14	DS	OF	
0000161C	E310 8EE8 0004		000010E8	885+	LG	R1, R1FUDGE	pollute R1
00001622	E710 5048 0006		00001648	886+	VL	V1, RE14+8	get V1 source
00001628	E611 0090 0050			887+	VCVB	R1, V1, 9	test instruction
0000162E	E310 8F20 0024		00001120	888+	STG	R1, R10OUTPUT	save
00001634	B98D 0020			889+	EPSW	R2, R0	exptract psw

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001638	5020 8ED8		000010D8	890+	ST	R2, CCPSW	to save CC
0000163C	07FB			891+	BR	R11	return
00001640				892+RE14	DC	0F	
00001640				893+	DROP	R5	
00001640	AABBCCDD 7FFFFFFF			894	DC	XL08' AABBCCDD7FFFFFFF'	R1 result
00001648	00000000 00000000			895	DC	XL16' 000000000000000000000002147483647C'	V1 source
00001650	00000214 7483647C						
				896			
				897	VRR_I	VCVB, 9, 3	INT_MIN
00001658				898+	DS	0FD	
00001658		00001658		899+	USING	*, R5	base for test data and test routine
00001658	00001674			900+T15	DC	A(X15)	address of test routine
0000165C	000F			901+	DC	H' 15'	test number
0000165E	00			902+	DC	XL1' 00'	
0000165F	09			903+	DC	HL1' 9'	&MB
00001660	03			904+	DC	HL1' 3'	cc
00001661	0E			905+	DC	HL1' 14'	cc failed mask
00001662	E5C3E5C2 40404040			906+	DC	CL8' VCVB'	instruction name
0000166C	00000010			907+	DC	A(16)	result length
00001670	00001698			908+REA15	DC	A(RE15)	result address
				909+*			INSTRUCTION UNDER TEST ROUTINE
00001674				910+X15	DS	0F	
00001674	E310 8EE8 0004		000010E8	911+	LG	R1, R1FUDGE	pollute R1
0000167A	E710 5048 0006		000016A0	912+	VL	V1, RE15+8	get V1 source
00001680	E611 0090 0050			913+	VCVB	R1, V1, 9	test instruction
00001686	E310 8F20 0024		00001120	914+	STG	R1, R10UTPUT	save
0000168C	B98D 0020			915+	EPSW	R2, R0	exptract psw
00001690	5020 8ED8		000010D8	916+	ST	R2, CCPSW	to save CC
00001694	07FB			917+	BR	R11	return
00001698				918+RE15	DC	0F	
00001698				919+	DROP	R5	
00001698	AABBCCDD 80000000			920	DC	XL08' AABBCCDD80000000'	R1 result
000016A0	00000000 00000000			921	DC	XL16' 000000000000000000000002147483648D'	V1 source
000016A8	00000214 7483648D						
				922			
				923	VRR_I	VCVB, 11, 0	UINT_MAX
000016B0				924+	DS	0FD	
000016B0		000016B0		925+	USING	*, R5	base for test data and test routine
000016B0	000016CC			926+T16	DC	A(X16)	address of test routine
000016B4	0010			927+	DC	H' 16'	test number
000016B6	00			928+	DC	XL1' 00'	
000016B7	0B			929+	DC	HL1' 11'	&MB
000016B8	00			930+	DC	HL1' 0'	cc
000016B9	07			931+	DC	HL1' 7'	cc failed mask
000016BA	E5C3E5C2 40404040			932+	DC	CL8' VCVB'	instruction name
000016C4	00000010			933+	DC	A(16)	result length
000016C8	000016F0			934+REA16	DC	A(RE16)	result address
				935+*			INSTRUCTION UNDER TEST ROUTINE
000016CC				936+X16	DS	0F	
000016CC	E310 8EE8 0004		000010E8	937+	LG	R1, R1FUDGE	pollute R1
000016D2	E710 5048 0006		000016F8	938+	VL	V1, RE16+8	get V1 source
000016D8	E611 00B0 0050			939+	VCVB	R1, V1, 11	test instruction
000016DE	E310 8F20 0024		00001120	940+	STG	R1, R10UTPUT	save
000016E4	B98D 0020			941+	EPSW	R2, R0	exptract psw
000016E8	5020 8ED8		000010D8	942+	ST	R2, CCPSW	to save CC
000016EC	07FB			943+	BR	R11	return



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000016F0				944+RE16	DC	0F	
000016F0				945+	DROP	R5	
000016F0	AABBCCDD FFFFFFFF			946	DC	XL08' AABBCCDDFFFFFFFF'	R1 result
000016F8	00000000 00000000			947	DC	XL16' 0000000000000000000000004294967295C'	V1 source
00001700	00000429 4967295C						
				948			
				949	VRR_I	VCVB, 11, 3	UINT_MAX +1
00001708				950+	DS	0FD	
00001708		00001708		951+	USING	*, R5	base for test data and test routine
00001708	00001724			952+T17	DC	A(X17)	address of test routine
0000170C	0011			953+	DC	H' 17'	test number
0000170E	00			954+	DC	XL1' 00'	
0000170F	0B			955+	DC	HL1' 11'	&MB
00001710	03			956+	DC	HL1' 3'	cc
00001711	0E			957+	DC	HL1' 14'	cc failed mask
00001712	E5C3E5C2 40404040			958+	DC	CL8' VCVB'	instruction name
0000171C	00000010			959+	DC	A(16)	result length
00001720	00001748			960+REA17	DC	A(RE17)	result address
				961+*			INSTRUCTION UNDER TEST ROUTINE
00001724				962+X17	DS	0F	
00001724	E310 8EE8 0004		000010E8	963+	LG	R1, R1FUDGE	pollute R1
0000172A	E710 5048 0006		00001750	964+	VL	V1, RE17+8	get V1 source
00001730	E611 00B0 0050			965+	VCVB	R1, V1, 11	test instruction
00001736	E310 8F20 0024		00001120	966+	STG	R1, R10UTPUT	save
0000173C	B98D 0020			967+	EPSW	R2, R0	exptract psw
00001740	5020 8ED8		000010D8	968+	ST	R2, CCPSW	to save CC
00001744	07FB			969+	BR	R11	return
00001748				970+RE17	DC	0F	
00001748				971+	DROP	R5	
00001748	AABBCCDD 00000000			972	DC	XL08' AABBCCDD00000000'	R1 result
00001750	00000000 00000000			973	DC	XL16' 0000000000000000000000004294967296C'	V1 source
00001758	00000429 4967296C						
				974			
				975	VRR_I	VCVB, 9, 3	
00001760				976+	DS	0FD	
00001760		00001760		977+	USING	*, R5	base for test data and test routine
00001760	0000177C			978+T18	DC	A(X18)	address of test routine
00001764	0012			979+	DC	H' 18'	test number
00001766	00			980+	DC	XL1' 00'	
00001767	09			981+	DC	HL1' 9'	&MB
00001768	03			982+	DC	HL1' 3'	cc
00001769	0E			983+	DC	HL1' 14'	cc failed mask
0000176A	E5C3E5C2 40404040			984+	DC	CL8' VCVB'	instruction name
00001774	00000010			985+	DC	A(16)	result length
00001778	000017A0			986+REA18	DC	A(RE18)	result address
				987+*			INSTRUCTION UNDER TEST ROUTINE
0000177C				988+X18	DS	0F	
0000177C	E310 8EE8 0004		000010E8	989+	LG	R1, R1FUDGE	pollute R1
00001782	E710 5048 0006		000017A8	990+	VL	V1, RE18+8	get V1 source
00001788	E611 0090 0050			991+	VCVB	R1, V1, 9	test instruction
0000178E	E310 8F20 0024		00001120	992+	STG	R1, R10UTPUT	save
00001794	B98D 0020			993+	EPSW	R2, R0	exptract psw
00001798	5020 8ED8		000010D8	994+	ST	R2, CCPSW	to save CC
0000179C	07FB			995+	BR	R11	return
000017A0				996+RE18	DC	0F	
000017A0				997+	DROP	R5	



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001850				1052+RE20	DC	0F	
00001850				1053+	DROP	R5	
00001850	FFFFFFFF FFFFFFFF6			1054	DC	XL08' FFFFFFFF6'	R1 result
00001858	00000000 00000000			1055	DC	XL16' 000000000000000000000000000010D'	V1 source
00001860	00000000 0000010D						
				1056			
				1057	VRR_I	VCVBG, 1, 0	
00001868				1058+	DS	0FD	
00001868		00001868		1059+	USING	*, R5	base for test data and test routine
00001868	00001884			1060+T21	DC	A(X21)	address of test routine
0000186C	0015			1061+	DC	H' 21'	test number
0000186E	00			1062+	DC	XL1' 00'	
0000186F	01			1063+	DC	HL1' 1'	&MB
00001870	00			1064+	DC	HL1' 0'	cc
00001871	07			1065+	DC	HL1' 7'	cc failed mask
00001872	E5C3E5C2 C7404040			1066+	DC	CL8' VCVBG'	instruction name
0000187C	00000010			1067+	DC	A(16)	result length
00001880	000018A8			1068+REA21	DC	A(RE21)	result address
				1069+*			INSTRUCTION UNDER TEST ROUTINE
00001884				1070+X21	DS	0F	
00001884	E310 8EE8 0004		000010E8	1071+	LG	R1, R1FUDGE	pollute R1
0000188A	E710 5048 0006		000018B0	1072+	VL	V1, RE21+8	get V1 source
00001890	E611 0010 0052			1073+	VCVBG	R1, V1, 1	test instruction
00001896	E310 8F20 0024		00001120	1074+	STG	R1, R10UTPUT	save
0000189C	B98D 0020			1075+	EPSW	R2, R0	exptract psw
000018A0	5020 8ED8		000010D8	1076+	ST	R2, CCPSW	to save CC
000018A4	07FB			1077+	BR	R11	return
000018A8				1078+RE21	DC	0F	
000018A8				1079+	DROP	R5	
000018A8	00000000 0008A160			1080	DC	XL08' 000000000008A160'	R1 result
000018B0	00000000 00000000			1081	DC	XL16' 0000000000000000000000000565600C'	V1 source
000018B8	00000000 0565600C						
				1082			
				1083	VRR_I	VCVBG, 1, 0	
000018C0				1084+	DS	0FD	
000018C0		000018C0		1085+	USING	*, R5	base for test data and test routine
000018C0	000018DC			1086+T22	DC	A(X22)	address of test routine
000018C4	0016			1087+	DC	H' 22'	test number
000018C6	00			1088+	DC	XL1' 00'	
000018C7	01			1089+	DC	HL1' 1'	&MB
000018C8	00			1090+	DC	HL1' 0'	cc
000018C9	07			1091+	DC	HL1' 7'	cc failed mask
000018CA	E5C3E5C2 C7404040			1092+	DC	CL8' VCVBG'	instruction name
000018D4	00000010			1093+	DC	A(16)	result length
000018D8	00001900			1094+REA22	DC	A(RE22)	result address
				1095+*			INSTRUCTION UNDER TEST ROUTINE
000018DC				1096+X22	DS	0F	
000018DC	E310 8EE8 0004		000010E8	1097+	LG	R1, R1FUDGE	pollute R1
000018E2	E710 5048 0006		00001908	1098+	VL	V1, RE22+8	get V1 source
000018E8	E611 0010 0052			1099+	VCVBG	R1, V1, 1	test instruction
000018EE	E310 8F20 0024		00001120	1100+	STG	R1, R10UTPUT	save
000018F4	B98D 0020			1101+	EPSW	R2, R0	exptract psw
000018F8	5020 8ED8		000010D8	1102+	ST	R2, CCPSW	to save CC
000018FC	07FB			1103+	BR	R11	return
00001900				1104+RE22	DC	0F	
00001900				1105+	DROP	R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001900	FFFFFFFF FFF75EA0			1106	DC	XL08' FFFFFFFFFF75EA0'	R1 result
00001908	00000000 00000000			1107	DC	XL16' 0000000000000000000000000565600D'	V1 source
00001910	00000000 0565600D						
				1108			
				1109	VRR_I	VCVBG, 1, 0	INT_MAX
00001918				1110+	DS	OFD	
00001918		00001918		1111+	USING	*, R5	base for test data and test routine
00001918	00001934			1112+T23	DC	A(X23)	address of test routine
0000191C	0017			1113+	DC	H' 23'	test number
0000191E	00			1114+	DC	XL1' 00'	
0000191F	01			1115+	DC	HL1' 1'	&MB
00001920	00			1116+	DC	HL1' 0'	cc
00001921	07			1117+	DC	HL1' 7'	cc failed mask
00001922	E5C3E5C2 C7404040			1118+	DC	CL8' VCVBG'	instruction name
0000192C	00000010			1119+	DC	A(16)	result length
00001930	00001958			1120+REA23	DC	A(RE23)	result address
				1121+*			INSTRUCTION UNDER TEST ROUTINE
00001934				1122+X23	DS	OF	
00001934	E310 8EE8 0004		000010E8	1123+	LG	R1, R1FUDGE	pollute R1
0000193A	E710 5048 0006		00001960	1124+	VL	V1, RE23+8	get V1 source
00001940	E611 0010 0052			1125+	VCVBG	R1, V1, 1	test instruction
00001946	E310 8F20 0024		00001120	1126+	STG	R1, R10UTPUT	save
0000194C	B98D 0020			1127+	EPSW	R2, R0	exptract psw
00001950	5020 8ED8		000010D8	1128+	ST	R2, CCPSW	to save CC
00001954	07FB			1129+	BR	R11	return
00001958				1130+RE23	DC	OF	
00001958				1131+	DROP	R5	
00001958	00000000 7FFFFFFF			1132	DC	XL08' 000000007FFFFFFF'	R1 result
00001960	00000000 00000000			1133	DC	XL16' 000000000000000000000002147483647C'	V1 source
00001968	00000214 7483647C						
				1134			
				1135	VRR_I	VCVBG, 1, 0	INT_MIN
00001970				1136+	DS	OFD	
00001970		00001970		1137+	USING	*, R5	base for test data and test routine
00001970	0000198C			1138+T24	DC	A(X24)	address of test routine
00001974	0018			1139+	DC	H' 24'	test number
00001976	00			1140+	DC	XL1' 00'	
00001977	01			1141+	DC	HL1' 1'	&MB
00001978	00			1142+	DC	HL1' 0'	cc
00001979	07			1143+	DC	HL1' 7'	cc failed mask
0000197A	E5C3E5C2 C7404040			1144+	DC	CL8' VCVBG'	instruction name
00001984	00000010			1145+	DC	A(16)	result length
00001988	000019B0			1146+REA24	DC	A(RE24)	result address
				1147+*			INSTRUCTION UNDER TEST ROUTINE
0000198C				1148+X24	DS	OF	
0000198C	E310 8EE8 0004		000010E8	1149+	LG	R1, R1FUDGE	pollute R1
00001992	E710 5048 0006		000019B8	1150+	VL	V1, RE24+8	get V1 source
00001998	E611 0010 0052			1151+	VCVBG	R1, V1, 1	test instruction
0000199E	E310 8F20 0024		00001120	1152+	STG	R1, R10UTPUT	save
000019A4	B98D 0020			1153+	EPSW	R2, R0	exptract psw
000019A8	5020 8ED8		000010D8	1154+	ST	R2, CCPSW	to save CC
000019AC	07FB			1155+	BR	R11	return
000019B0				1156+RE24	DC	OF	
000019B0				1157+	DROP	R5	
000019B0	FFFFFFFF 80000000			1158	DC	XL08' FFFFFFFFFF80000000'	R1 result
000019B8	00000000 00000000			1159	DC	XL16' 000000000000000000000002147483648D'	V1 source



LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000019C0	00000214 7483648D			1160		
				1161	VRR_I VCVBG, 1, 0	UINT_MAX
000019C8				1162+	DS OFD	
000019C8		000019C8		1163+	USING *, R5	base for test data and test routine
000019C8	000019E4			1164+T25	DC A(X25)	address of test routine
000019CC	0019			1165+	DC H' 25'	test number
000019CE	00			1166+	DC XL1' 00'	
000019CF	01			1167+	DC HL1' 1'	&MB
000019D0	00			1168+	DC HL1' 0'	cc
000019D1	07			1169+	DC HL1' 7'	cc failed mask
000019D2	E5C3E5C2 C7404040			1170+	DC CL8' VCVBG'	instruction name
000019DC	00000010			1171+	DC A(16)	result length
000019E0	00001A08			1172+REA25	DC A(RE25)	result address
				1173+*		INSTRUCTION UNDER TEST ROUTINE
000019E4				1174+X25	DS OF	
000019E4	E310 8EE8 0004		000010E8	1175+	LG R1, R1FUDGE	pollute R1
000019EA	E710 5048 0006		00001A10	1176+	VL V1, RE25+8	get V1 source
000019F0	E611 0010 0052			1177+	VCVBG R1, V1, 1	test instruction
000019F6	E310 8F20 0024		00001120	1178+	STG R1, R10UTPUT	save
000019FC	B98D 0020			1179+	EPSW R2, R0	exptract psw
00001A00	5020 8ED8		000010D8	1180+	ST R2, CCPSW	to save CC
00001A04	07FB			1181+	BR R11	return
00001A08				1182+RE25	DC OF	
00001A08				1183+	DROP R5	
00001A08	00000000 FFFFFFFF			1184	DC XL08' 00000000FFFFFFFF'	R1 result
00001A10	00000000 00000000			1185	DC XL16' 0000000000000000000000004294967295C'	V1 source
00001A18	00000429 4967295C					
				1186		
				1187	VRR_I VCVBG, 1, 0	UINT_MAX +1
00001A20				1188+	DS OFD	
00001A20		00001A20		1189+	USING *, R5	base for test data and test routine
00001A20	00001A3C			1190+T26	DC A(X26)	address of test routine
00001A24	001A			1191+	DC H' 26'	test number
00001A26	00			1192+	DC XL1' 00'	
00001A27	01			1193+	DC HL1' 1'	&MB
00001A28	00			1194+	DC HL1' 0'	cc
00001A29	07			1195+	DC HL1' 7'	cc failed mask
00001A2A	E5C3E5C2 C7404040			1196+	DC CL8' VCVBG'	instruction name
00001A34	00000010			1197+	DC A(16)	result length
00001A38	00001A60			1198+REA26	DC A(RE26)	result address
				1199+*		INSTRUCTION UNDER TEST ROUTINE
00001A3C				1200+X26	DS OF	
00001A3C	E310 8EE8 0004		000010E8	1201+	LG R1, R1FUDGE	pollute R1
00001A42	E710 5048 0006		00001A68	1202+	VL V1, RE26+8	get V1 source
00001A48	E611 0010 0052			1203+	VCVBG R1, V1, 1	test instruction
00001A4E	E310 8F20 0024		00001120	1204+	STG R1, R10UTPUT	save
00001A54	B98D 0020			1205+	EPSW R2, R0	exptract psw
00001A58	5020 8ED8		000010D8	1206+	ST R2, CCPSW	to save CC
00001A5C	07FB			1207+	BR R11	return
00001A60				1208+RE26	DC OF	
00001A60				1209+	DROP R5	
00001A60	00000001 00000000			1210	DC XL08' 0000000100000000'	R1 result
00001A68	00000000 00000000			1211	DC XL16' 0000000000000000000000004294967296C'	V1 source
00001A70	00000429 4967296C					
				1212		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001A78				1213	VRR_I	VCVBG, 1, 0	
00001A78				1214+	DS	OFD	
00001A78		00001A78		1215+	USING	*, R5	base for test data and test routine
00001A78	00001A94			1216+T27	DC	A(X27)	address of test routine
00001A7C	001B			1217+	DC	H' 27'	test number
00001A7E	00			1218+	DC	XL1' 00'	
00001A7F	01			1219+	DC	HL1' 1'	&MB
00001A80	00			1220+	DC	HL1' 0'	cc
00001A81	07			1221+	DC	HL1' 7'	cc failed mask
00001A82	E5C3E5C2 C7404040			1222+	DC	CL8' VCVBG'	instruction name
00001A8C	00000010			1223+	DC	A(16)	result length
00001A90	00001AB8			1224+REA27	DC	A(RE27)	result address
				1225+*			INSTRUCTION UNDER TEST ROUTINE
00001A94				1226+X27	DS	OF	
00001A94	E310 8EE8 0004		000010E8	1227+	LG	R1, R1FUDGE	pollute R1
00001A9A	E710 5048 0006		00001AC0	1228+	VL	V1, RE27+8	get V1 source
00001AA0	E611 0010 0052			1229+	VCVBG	R1, V1, 1	test instruction
00001AA6	E310 8F20 0024		00001120	1230+	STG	R1, R10UTPUT	save
00001AAC	B98D 0020			1231+	EPSW	R2, R0	exptract psw
00001AB0	5020 8ED8		000010D8	1232+	ST	R2, CCPSW	to save CC
00001AB4	07FB			1233+	BR	R11	return
00001AB8				1234+RE27	DC	OF	
00001AB8				1235+	DROP	R5	
00001AB8	00000002 DF8E1660			1236	DC	XL08' 00000002DF8E1660'	R1 result
00001AC0	00000000 00000000			1237	DC	XL16' 00000000000000000000000012340565600C'	V1 source
00001AC8	00001234 0565600C						
				1238			
00001AD0				1239	VRR_I	VCVBG, 1, 0	LONG_MAX
00001AD0				1240+	DS	OFD	
00001AD0		00001AD0		1241+	USING	*, R5	base for test data and test routine
00001AD0	00001AEC			1242+T28	DC	A(X28)	address of test routine
00001AD4	001C			1243+	DC	H' 28'	test number
00001AD6	00			1244+	DC	XL1' 00'	
00001AD7	01			1245+	DC	HL1' 1'	&MB
00001AD8	00			1246+	DC	HL1' 0'	cc
00001AD9	07			1247+	DC	HL1' 7'	cc failed mask
00001ADA	E5C3E5C2 C7404040			1248+	DC	CL8' VCVBG'	instruction name
00001AE4	00000010			1249+	DC	A(16)	result length
00001AE8	00001B10			1250+REA28	DC	A(RE28)	result address
				1251+*			INSTRUCTION UNDER TEST ROUTINE
00001AEC				1252+X28	DS	OF	
00001AEC	E310 8EE8 0004		000010E8	1253+	LG	R1, R1FUDGE	pollute R1
00001AF2	E710 5048 0006		00001B18	1254+	VL	V1, RE28+8	get V1 source
00001AF8	E611 0010 0052			1255+	VCVBG	R1, V1, 1	test instruction
00001AFE	E310 8F20 0024		00001120	1256+	STG	R1, R10UTPUT	save
00001B04	B98D 0020			1257+	EPSW	R2, R0	exptract psw
00001B08	5020 8ED8		000010D8	1258+	ST	R2, CCPSW	to save CC
00001B0C	07FB			1259+	BR	R11	return
00001B10				1260+RE28	DC	OF	
00001B10				1261+	DROP	R5	
00001B10	7FFFFFFF FFFFFFFF			1262	DC	XL08' 7FFFFFFF7FFFFFFF'	R1 result
00001B18	00000000 00009223			1263	DC	XL16' 000000000000009223372036854775807C'	V1 source
00001B20	37203685 4775807C						
				1264			
00001B28				1265	VRR_I	VCVBG, 1, 0	LONG_MIN
				1266+	DS	OFD	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001B28		00001B28		1267+	USING *,R5	base for test data and test routine
00001B28	00001B44			1268+T29	DC A(X29)	address of test routine
00001B2C	001D			1269+	DC H' 29'	test number
00001B2E	00			1270+	DC XL1' 00'	
00001B2F	01			1271+	DC HL1' 1'	&MB
00001B30	00			1272+	DC HL1' 0'	cc
00001B31	07			1273+	DC HL1' 7'	cc failed mask
00001B32	E5C3E5C2 C7404040			1274+	DC CL8' VCVBG'	instruction name
00001B3C	00000010			1275+	DC A(16)	result length
00001B40	00001B68			1276+REA29	DC A(RE29)	result address
				1277+*		INSTRUCTION UNDER TEST ROUTINE
00001B44				1278+X29	DS 0F	
00001B44	E310 8EE8 0004		000010E8	1279+	LG R1, R1FUDGE	pollute R1
00001B4A	E710 5048 0006		00001B70	1280+	VL V1, RE29+8	get V1 source
00001B50	E611 0010 0052			1281+	VCVBG R1, V1, 1	test instruction
00001B56	E310 8F20 0024		00001120	1282+	STG R1, R10UTPUT	save
00001B5C	B98D 0020			1283+	EPSW R2, R0	exptract psw
00001B60	5020 8ED8		000010D8	1284+	ST R2, CCPSW	to save CC
00001B64	07FB			1285+	BR R11	return
00001B68				1286+RE29	DC 0F	
00001B68				1287+	DROP R5	
00001B68	80000000 00000000			1288	DC XL08' 8000000000000000'	R1 result
00001B70	00000000 00009223			1289	DC XL16' 0000000000009223372036854775808D'	V1 source
00001B78	37203685 4775808D					
				1290		
				1291	VRR_I VCVBG, 3, 0	ULONG_MAX
00001B80				1292+	DS 0FD	
00001B80		00001B80		1293+	USING *,R5	base for test data and test routine
00001B80	00001B9C			1294+T30	DC A(X30)	address of test routine
00001B84	001E			1295+	DC H' 30'	test number
00001B86	00			1296+	DC XL1' 00'	
00001B87	03			1297+	DC HL1' 3'	&MB
00001B88	00			1298+	DC HL1' 0'	cc
00001B89	07			1299+	DC HL1' 7'	cc failed mask
00001B8A	E5C3E5C2 C7404040			1300+	DC CL8' VCVBG'	instruction name
00001B94	00000010			1301+	DC A(16)	result length
00001B98	00001BC0			1302+REA30	DC A(RE30)	result address
				1303+*		INSTRUCTION UNDER TEST ROUTINE
00001B9C				1304+X30	DS 0F	
00001B9C	E310 8EE8 0004		000010E8	1305+	LG R1, R1FUDGE	pollute R1
00001BA2	E710 5048 0006		00001BC8	1306+	VL V1, RE30+8	get V1 source
00001BA8	E611 0030 0052			1307+	VCVBG R1, V1, 3	test instruction
00001BAE	E310 8F20 0024		00001120	1308+	STG R1, R10UTPUT	save
00001BB4	B98D 0020			1309+	EPSW R2, R0	exptract psw
00001BB8	5020 8ED8		000010D8	1310+	ST R2, CCPSW	to save CC
00001BBC	07FB			1311+	BR R11	return
00001BC0				1312+RE30	DC 0F	
00001BC0				1313+	DROP R5	
00001BC0	FFFFFFFF FFFFFFFF			1314	DC XL08' FFFFFFFFFFFFFFFFFF'	R1 result
00001BC8	00000000 00018446			1315	DC XL16' 0000000000018446744073709551615C'	V1 source
00001BD0	74407370 9551615C					
				1316		
				1317	VRR_I VCVBG, 3, 3	ULONG_MAX +1
00001BD8				1318+	DS 0FD	
00001BD8		00001BD8		1319+	USING *,R5	base for test data and test routine
00001BD8	00001BF4			1320+T31	DC A(X31)	address of test routine



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001BDC	001F			1321+	DC	H' 31'	test number
00001BDE	00			1322+	DC	XL1' 00'	
00001BDF	03			1323+	DC	HL1' 3'	&MB
00001BE0	03			1324+	DC	HL1' 3'	cc
00001BE1	0E			1325+	DC	HL1' 14'	cc failed mask
00001BE2	E5C3E5C2 C7404040			1326+	DC	CL8' VCVBG'	instruction name
00001BEC	00000010			1327+	DC	A(16)	result length
00001BF0	00001C18			1328+REA31	DC	A(RE31)	result address
				1329+*			INSTRUCTION UNDER TEST ROUTINE
00001BF4				1330+X31	DS	0F	
00001BF4	E310 8EE8 0004		000010E8	1331+	LG	R1, R1FUDGE	pollute R1
00001BFA	E710 5048 0006		00001C20	1332+	VL	V1, RE31+8	get V1 source
00001C00	E611 0030 0052			1333+	VCVBG	R1, V1, 3	test instruction
00001C06	E310 8F20 0024		00001120	1334+	STG	R1, R10UTPUT	save
00001C0C	B98D 0020			1335+	EPSW	R2, R0	exptract psw
00001C10	5020 8ED8		000010D8	1336+	ST	R2, CCPSW	to save CC
00001C14	07FB			1337+	BR	R11	return
00001C18				1338+RE31	DC	0F	
00001C18				1339+	DROP	R5	
00001C18	00000000 00000000			1340	DC	XL08' 00000000000000000'	R1 result
00001C20	00000000 00018446			1341	DC	XL16' 0000000000018446744073709551616C'	V1 source
00001C28	74407370 9551616C						
				1342			
00001C30				1343	VRR_I	VCVBG, 3, 3	ULONG_MAX +11
00001C30		00001C30		1344+	DS	0FD	
00001C30	00001C4C			1345+	USING	*, R5	base for test data and test routine
00001C34	0020			1346+T32	DC	A(X32)	address of test routine
00001C36	00			1347+	DC	H' 32'	test number
00001C36	00			1348+	DC	XL1' 00'	
00001C37	03			1349+	DC	HL1' 3'	&MB
00001C38	03			1350+	DC	HL1' 3'	cc
00001C39	0E			1351+	DC	HL1' 14'	cc failed mask
00001C3A	E5C3E5C2 C7404040			1352+	DC	CL8' VCVBG'	instruction name
00001C44	00000010			1353+	DC	A(16)	result length
00001C48	00001C70			1354+REA32	DC	A(RE32)	result address
				1355+*			INSTRUCTION UNDER TEST ROUTINE
00001C4C				1356+X32	DS	0F	
00001C4C	E310 8EE8 0004		000010E8	1357+	LG	R1, R1FUDGE	pollute R1
00001C52	E710 5048 0006		00001C78	1358+	VL	V1, RE32+8	get V1 source
00001C58	E611 0030 0052			1359+	VCVBG	R1, V1, 3	test instruction
00001C5E	E310 8F20 0024		00001120	1360+	STG	R1, R10UTPUT	save
00001C64	B98D 0020			1361+	EPSW	R2, R0	exptract psw
00001C68	5020 8ED8		000010D8	1362+	ST	R2, CCPSW	to save CC
00001C6C	07FB			1363+	BR	R11	return
00001C70				1364+RE32	DC	0F	
00001C70				1365+	DROP	R5	
00001C70	00000000 0000000A			1366	DC	XL08' 0000000000000000A'	R1 result
00001C78	00000000 00018446			1367	DC	XL16' 0000000000018446744073709551626C'	V1 source
00001C80	74407370 9551626C						
				1368			
				1369 * VCVBG simple: p2=1			
00001C88				1370	VRR_I	VCVBG, 9, 0	
00001C88		00001C88		1371+	DS	0FD	
00001C88	00001CA4			1372+	USING	*, R5	base for test data and test routine
00001C88	0021			1373+T33	DC	A(X33)	address of test routine
00001C8C				1374+	DC	H' 33'	test number

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001C8E	00			1375+	DC	XL1' 00'	
00001C8F	09			1376+	DC	HL1' 9'	&MB
00001C90	00			1377+	DC	HL1' 0'	cc
00001C91	07			1378+	DC	HL1' 7'	cc failed mask
00001C92	E5C3E5C2 C7404040			1379+	DC	CL8' VCVBG'	instruction name
00001C9C	00000010			1380+	DC	A(16)	result length
00001CA0	00001CC8			1381+REA33	DC	A(RE33)	result address
				1382+*			INSTRUCTION UNDER TEST ROUTINE
00001CA4				1383+X33	DS	0F	
00001CA4	E310 8EE8 0004		000010E8	1384+	LG	R1, R1FUDGE	pollute R1
00001CAA	E710 5048 0006		00001CD0	1385+	VL	V1, RE33+8	get V1 source
00001CB0	E611 0090 0052			1386+	VCVBG	R1, V1, 9	test instruction
00001CB6	E310 8F20 0024		00001120	1387+	STG	R1, R10UTPUT	save
00001CBC	B98D 0020			1388+	EPSW	R2, R0	exptract psw
00001CC0	5020 8ED8		000010D8	1389+	ST	R2, CCPSW	to save CC
00001CC4	07FB			1390+	BR	R11	return
00001CC8				1391+RE33	DC	0F	
00001CC8				1392+	DROP	R5	
00001CC8	00000000 0000000A			1393	DC	XL08' 0000000000000000A'	R1 result
00001CD0	00000000 00000000			1394	DC	XL16' 0000000000000000000000000000000010C'	V1 source
00001CD8	00000000 0000010C						
				1395			
				1396	VRR_I	VCVBG, 9, 0	
00001CE0				1397+	DS	0FD	
00001CE0		00001CE0		1398+	USING	*, R5	base for test data and test routine
00001CE0	00001CFC			1399+T34	DC	A(X34)	address of test routine
00001CE4	0022			1400+	DC	H' 34'	test number
00001CE6	00			1401+	DC	XL1' 00'	
00001CE7	09			1402+	DC	HL1' 9'	&MB
00001CE8	00			1403+	DC	HL1' 0'	cc
00001CE9	07			1404+	DC	HL1' 7'	cc failed mask
00001CEA	E5C3E5C2 C7404040			1405+	DC	CL8' VCVBG'	instruction name
00001CF4	00000010			1406+	DC	A(16)	result length
00001CF8	00001D20			1407+REA34	DC	A(RE34)	result address
				1408+*			INSTRUCTION UNDER TEST ROUTINE
00001CFC				1409+X34	DS	0F	
00001CFC	E310 8EE8 0004		000010E8	1410+	LG	R1, R1FUDGE	pollute R1
00001D02	E710 5048 0006		00001D28	1411+	VL	V1, RE34+8	get V1 source
00001D08	E611 0090 0052			1412+	VCVBG	R1, V1, 9	test instruction
00001D0E	E310 8F20 0024		00001120	1413+	STG	R1, R10UTPUT	save
00001D14	B98D 0020			1414+	EPSW	R2, R0	exptract psw
00001D18	5020 8ED8		000010D8	1415+	ST	R2, CCPSW	to save CC
00001D1C	07FB			1416+	BR	R11	return
00001D20				1417+RE34	DC	0F	
00001D20				1418+	DROP	R5	
00001D20	00000000 0000000A			1419	DC	XL08' 0000000000000000A'	R1 result
00001D28	00000000 00000000			1420	DC	XL16' 0000000000000000000000000000000010D'	V1 source
00001D30	00000000 0000010D						
				1421			
				1422	VRR_I	VCVBG, 9, 0	
00001D38				1423+	DS	0FD	
00001D38		00001D38		1424+	USING	*, R5	base for test data and test routine
00001D38	00001D54			1425+T35	DC	A(X35)	address of test routine
00001D3C	0023			1426+	DC	H' 35'	test number
00001D3E	00			1427+	DC	XL1' 00'	
00001D3F	09			1428+	DC	HL1' 9'	&MB

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001D40	00			1429+	DC	HL1' 0'	cc
00001D41	07			1430+	DC	HL1' 7'	cc failed mask
00001D42	E5C3E5C2 C7404040			1431+	DC	CL8' VCVBG'	instruction name
00001D4C	00000010			1432+	DC	A(16)	result length
00001D50	00001D78			1433+REA35	DC	A(RE35)	result address
				1434+*			INSTRUCTION UNDER TEST ROUTINE
00001D54				1435+X35	DS	OF	
00001D54	E310 8EE8 0004		000010E8	1436+	LG	R1, R1FUDGE	pollute R1
00001D5A	E710 5048 0006		00001D80	1437+	VL	V1, RE35+8	get V1 source
00001D60	E611 0090 0052			1438+	VCVBG	R1, V1, 9	test instruction
00001D66	E310 8F20 0024		00001120	1439+	STG	R1, R10UTPUT	save
00001D6C	B98D 0020			1440+	EPSW	R2, R0	exptract psw
00001D70	5020 8ED8		000010D8	1441+	ST	R2, CCPSW	to save CC
00001D74	07FB			1442+	BR	R11	return
00001D78				1443+RE35	DC	OF	
00001D78				1444+	DROP	R5	
00001D78	00000000 0008A160			1445	DC	XL08' 0000000000008A160'	R1 result
00001D80	00000000 00000000			1446	DC	XL16' 0000000000000000000000000565600C'	V1 source
00001D88	00000000 0565600C						
				1447			
				1448	VRR_I	VCVBG, 9, 0	
00001D90				1449+	DS	OFD	
00001D90		00001D90		1450+	USING	*, R5	base for test data and test routine
00001D90	00001DAC			1451+T36	DC	A(X36)	address of test routine
00001D94	0024			1452+	DC	H' 36'	test number
00001D96	00			1453+	DC	XL1' 00'	
00001D97	09			1454+	DC	HL1' 9'	&MB
00001D98	00			1455+	DC	HL1' 0'	cc
00001D99	07			1456+	DC	HL1' 7'	cc failed mask
00001D9A	E5C3E5C2 C7404040			1457+	DC	CL8' VCVBG'	instruction name
00001DA4	00000010			1458+	DC	A(16)	result length
00001DA8	00001DD0			1459+REA36	DC	A(RE36)	result address
				1460+*			INSTRUCTION UNDER TEST ROUTINE
00001DAC				1461+X36	DS	OF	
00001DAC	E310 8EE8 0004		000010E8	1462+	LG	R1, R1FUDGE	pollute R1
00001DB2	E710 5048 0006		00001DD8	1463+	VL	V1, RE36+8	get V1 source
00001DB8	E611 0090 0052			1464+	VCVBG	R1, V1, 9	test instruction
00001DBE	E310 8F20 0024		00001120	1465+	STG	R1, R10UTPUT	save
00001DC4	B98D 0020			1466+	EPSW	R2, R0	exptract psw
00001DC8	5020 8ED8		000010D8	1467+	ST	R2, CCPSW	to save CC
00001DCC	07FB			1468+	BR	R11	return
00001DD0				1469+RE36	DC	OF	
00001DD0				1470+	DROP	R5	
00001DD0	00000000 0008A160			1471	DC	XL08' 0000000000008A160'	R1 result
00001DD8	00000000 00000000			1472	DC	XL16' 0000000000000000000000000565600D'	V1 source
00001DE0	00000000 0565600D						
				1473			
				1474	VRR_I	VCVBG, 9, 0	INT_MAX
00001DE8				1475+	DS	OFD	
00001DE8		00001DE8		1476+	USING	*, R5	base for test data and test routine
00001DE8	00001E04			1477+T37	DC	A(X37)	address of test routine
00001DEC	0025			1478+	DC	H' 37'	test number
00001DEE	00			1479+	DC	XL1' 00'	
00001DEF	09			1480+	DC	HL1' 9'	&MB
00001DF0	00			1481+	DC	HL1' 0'	cc
00001DF1	07			1482+	DC	HL1' 7'	cc failed mask

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001DF2	E5C3E5C2 C7404040			1483+	DC	CL8' VCVBG'	instruction name
00001DFC	00000010			1484+	DC	A(16)	result length
00001E00	00001E28			1485+REA37	DC	A(RE37)	result address
				1486+*			INSTRUCTION UNDER TEST ROUTINE
00001E04				1487+X37	DS	0F	
00001E04	E310 8EE8 0004		000010E8	1488+	LG	R1, R1FUDGE	pollute R1
00001E0A	E710 5048 0006		00001E30	1489+	VL	V1, RE37+8	get V1 source
00001E10	E611 0090 0052			1490+	VCVBG	R1, V1, 9	test instruction
00001E16	E310 8F20 0024		00001120	1491+	STG	R1, R10UTPUT	save
00001E1C	B98D 0020			1492+	EPSW	R2, R0	exptract psw
00001E20	5020 8ED8		000010D8	1493+	ST	R2, CCPSW	to save CC
00001E24	07FB			1494+	BR	R11	return
00001E28				1495+RE37	DC	0F	
00001E28				1496+	DROP	R5	
00001E28	00000000 7FFFFFFF			1497	DC	XL08' 000000007FFFFFFF'	R1 result
00001E30	00000000 00000000			1498	DC	XL16' 000000000000000000000002147483647C'	V1 source
00001E38	00000214 7483647C						
				1499			
00001E40				1500	VRR_I	VCVBG, 9, 0	INT_MIN
00001E40		00001E40		1501+	DS	0FD	
00001E40	00001E5C			1502+	USING	*, R5	base for test data and test routine
00001E44	0026			1503+T38	DC	A(X38)	address of test routine
00001E46	00			1504+	DC	H' 38'	test number
00001E47	09			1505+	DC	XL1' 00'	
00001E48	00			1506+	DC	HL1' 9'	&MB
00001E49	07			1507+	DC	HL1' 0'	cc
00001E4A	E5C3E5C2 C7404040			1508+	DC	HL1' 7'	cc failed mask
00001E54	00000010			1509+	DC	CL8' VCVBG'	instruction name
00001E58	00001E80			1510+	DC	A(16)	result length
				1511+REA38	DC	A(RE38)	result address
				1512+*			INSTRUCTION UNDER TEST ROUTINE
00001E5C				1513+X38	DS	0F	
00001E5C	E310 8EE8 0004		000010E8	1514+	LG	R1, R1FUDGE	pollute R1
00001E62	E710 5048 0006		00001E88	1515+	VL	V1, RE38+8	get V1 source
00001E68	E611 0090 0052			1516+	VCVBG	R1, V1, 9	test instruction
00001E6E	E310 8F20 0024		00001120	1517+	STG	R1, R10UTPUT	save
00001E74	B98D 0020			1518+	EPSW	R2, R0	exptract psw
00001E78	5020 8ED8		000010D8	1519+	ST	R2, CCPSW	to save CC
00001E7C	07FB			1520+	BR	R11	return
00001E80				1521+RE38	DC	0F	
00001E80				1522+	DROP	R5	
00001E80	00000000 80000000			1523	DC	XL08' 0000000080000000'	R1 result
00001E88	00000000 00000000			1524	DC	XL16' 000000000000000000000002147483648D'	V1 source
00001E90	00000214 7483648D						
				1525			
00001E98				1526	VRR_I	VCVBG, 9, 0	UINT_MAX
00001E98		00001E98		1527+	DS	0FD	
00001E98	00001EB4			1528+	USING	*, R5	base for test data and test routine
00001E9C	0027			1529+T39	DC	A(X39)	address of test routine
00001E9E	00			1530+	DC	H' 39'	test number
00001E9F	09			1531+	DC	XL1' 00'	
00001EA0	00			1532+	DC	HL1' 9'	&MB
00001EA1	07			1533+	DC	HL1' 0'	cc
00001EA2	E5C3E5C2 C7404040			1534+	DC	HL1' 7'	cc failed mask
00001EAC	00000010			1535+	DC	CL8' VCVBG'	instruction name
				1536+	DC	A(16)	result length



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001EB0	00001ED8			1537+REA39	DC	A(RE39)	result address
				1538+*			INSTRUCTION UNDER TEST ROUTINE
00001EB4				1539+X39	DS	0F	
00001EB4	E310 8EE8 0004		000010E8	1540+	LG	R1, R1FUDGE	pollute R1
00001EBA	E710 5048 0006		00001EE0	1541+	VL	V1, RE39+8	get V1 source
00001EC0	E611 0090 0052			1542+	VCVBG	R1, V1, 9	test instruction
00001EC6	E310 8F20 0024		00001120	1543+	STG	R1, R10UTPUT	save
00001ECC	B98D 0020			1544+	EPSW	R2, R0	exptract psw
00001ED0	5020 8ED8		000010D8	1545+	ST	R2, CCPSW	to save CC
00001ED4	07FB			1546+	BR	R11	return
00001ED8				1547+RE39	DC	0F	
00001ED8				1548+	DROP	R5	
00001ED8	00000000 FFFFFFFF			1549	DC	XL08' 00000000FFFFFFFF'	R1 result
00001EE0	00000000 00000000			1550	DC	XL16' 0000000000000000000000004294967295C'	V1 source
00001EE8	00000429 4967295C						
				1551			
				1552	VRR_I	VCVBG, 9, 0	UINT_MAX +1
00001EF0				1553+	DS	0FD	
00001EF0		00001EF0		1554+	USING	*, R5	base for test data and test routine
00001EF0	00001F0C			1555+T40	DC	A(X40)	address of test routine
00001EF4	0028			1556+	DC	H' 40'	test number
00001EF6	00			1557+	DC	XL1' 00'	
00001EF7	09			1558+	DC	HL1' 9'	&MB
00001EF8	00			1559+	DC	HL1' 0'	cc
00001EF9	07			1560+	DC	HL1' 7'	cc failed mask
00001EFA	E5C3E5C2 C7404040			1561+	DC	CL8' VCVBG'	instruction name
00001F04	00000010			1562+	DC	A(16)	result length
00001F08	00001F30			1563+REA40	DC	A(RE40)	result address
				1564+*			INSTRUCTION UNDER TEST ROUTINE
00001F0C				1565+X40	DS	0F	
00001F0C	E310 8EE8 0004		000010E8	1566+	LG	R1, R1FUDGE	pollute R1
00001F12	E710 5048 0006		00001F38	1567+	VL	V1, RE40+8	get V1 source
00001F18	E611 0090 0052			1568+	VCVBG	R1, V1, 9	test instruction
00001F1E	E310 8F20 0024		00001120	1569+	STG	R1, R10UTPUT	save
00001F24	B98D 0020			1570+	EPSW	R2, R0	exptract psw
00001F28	5020 8ED8		000010D8	1571+	ST	R2, CCPSW	to save CC
00001F2C	07FB			1572+	BR	R11	return
00001F30				1573+RE40	DC	0F	
00001F30				1574+	DROP	R5	
00001F30	00000001 00000000			1575	DC	XL08' 0000000100000000'	R1 result
00001F38	00000000 00000000			1576	DC	XL16' 0000000000000000000000004294967296C'	V1 source
00001F40	00000429 4967296C						
				1577			
				1578	VRR_I	VCVBG, 9, 0	
00001F48				1579+	DS	0FD	
00001F48		00001F48		1580+	USING	*, R5	base for test data and test routine
00001F48	00001F64			1581+T41	DC	A(X41)	address of test routine
00001F4C	0029			1582+	DC	H' 41'	test number
00001F4E	00			1583+	DC	XL1' 00'	
00001F4F	09			1584+	DC	HL1' 9'	&MB
00001F50	00			1585+	DC	HL1' 0'	cc
00001F51	07			1586+	DC	HL1' 7'	cc failed mask
00001F52	E5C3E5C2 C7404040			1587+	DC	CL8' VCVBG'	instruction name
00001F5C	00000010			1588+	DC	A(16)	result length
00001F60	00001F88			1589+REA41	DC	A(RE41)	result address
				1590+*			INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001F64				1591+X41	DS	OF	
00001F64	E310 8EE8 0004		000010E8	1592+	LG	R1, R1FUDGE	pollute R1
00001F6A	E710 5048 0006		00001F90	1593+	VL	V1, RE41+8	get V1 source
00001F70	E611 0090 0052			1594+	VCVBG	R1, V1, 9	test instruction
00001F76	E310 8F20 0024		00001120	1595+	STG	R1, R10UTPUT	save
00001F7C	B98D 0020			1596+	EPSW	R2, R0	exptract psw
00001F80	5020 8ED8		000010D8	1597+	ST	R2, CCPSW	to save CC
00001F84	07FB			1598+	BR	R11	return
00001F88				1599+RE41	DC	OF	
00001F88				1600+	DROP	R5	
00001F88	00000002 DF8E1660			1601	DC	XL08' 00000002DF8E1660'	R1 result
00001F90	00000000 00000000			1602	DC	XL16' 00000000000000000000000012340565600C'	V1 source
00001F98	00001234 0565600C						
				1603			
				1604	VRR_I	VCVBG, 9, 0	LONG_MAX
00001FA0				1605+	DS	OFD	
00001FA0		00001FA0		1606+	USING	*, R5	base for test data and test routine
00001FA0	00001FBC			1607+T42	DC	A(X42)	address of test routine
00001FA4	002A			1608+	DC	H' 42'	test number
00001FA6	00			1609+	DC	XL1' 00'	
00001FA7	09			1610+	DC	HL1' 9'	&MB
00001FA8	00			1611+	DC	HL1' 0'	cc
00001FA9	07			1612+	DC	HL1' 7'	cc failed mask
00001FAA	E5C3E5C2 C7404040			1613+	DC	CL8' VCVBG'	instruction name
00001FB4	00000010			1614+	DC	A(16)	result length
00001FB8	00001FE0			1615+REA42	DC	A(RE42)	result address
				1616+*			INSTRUCTION UNDER TEST ROUTINE
00001FBC				1617+X42	DS	OF	
00001FBC	E310 8EE8 0004		000010E8	1618+	LG	R1, R1FUDGE	pollute R1
00001FC2	E710 5048 0006		00001FE8	1619+	VL	V1, RE42+8	get V1 source
00001FC8	E611 0090 0052			1620+	VCVBG	R1, V1, 9	test instruction
00001FCE	E310 8F20 0024		00001120	1621+	STG	R1, R10UTPUT	save
00001FD4	B98D 0020			1622+	EPSW	R2, R0	exptract psw
00001FD8	5020 8ED8		000010D8	1623+	ST	R2, CCPSW	to save CC
00001FDC	07FB			1624+	BR	R11	return
00001FE0				1625+RE42	DC	OF	
00001FE0				1626+	DROP	R5	
00001FE0	7FFFFFFF FFFFFFFF			1627	DC	XL08' 7FFFFFFF7FFFFFFF'	R1 result
00001FE8	00000000 00009223			1628	DC	XL16' 0000000000009223372036854775807C'	V1 source
00001FF0	37203685 4775807C						
				1629			
				1630	VRR_I	VCVBG, 9, 3	LONG_MIN
00001FF8				1631+	DS	OFD	
00001FF8		00001FF8		1632+	USING	*, R5	base for test data and test routine
00001FF8	00002014			1633+T43	DC	A(X43)	address of test routine
00001FFC	002B			1634+	DC	H' 43'	test number
00001FFE	00			1635+	DC	XL1' 00'	
00001FFF	09			1636+	DC	HL1' 9'	&MB
00002000	03			1637+	DC	HL1' 3'	cc
00002001	0E			1638+	DC	HL1' 14'	cc failed mask
00002002	E5C3E5C2 C7404040			1639+	DC	CL8' VCVBG'	instruction name
0000200C	00000010			1640+	DC	A(16)	result length
00002010	00002038			1641+REA43	DC	A(RE43)	result address
				1642+*			INSTRUCTION UNDER TEST ROUTINE
00002014				1643+X43	DS	OF	
00002014	E310 8EE8 0004		000010E8	1644+	LG	R1, R1FUDGE	pollute R1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000201A	E710 5048 0006		00002040	1645+	VL	V1, RE43+8	get V1 source
00002020	E611 0090 0052			1646+	VCVBG	R1, V1, 9	test instruction
00002026	E310 8F20 0024		00001120	1647+	STG	R1, R10UTPUT	save
0000202C	B98D 0020			1648+	EPSW	R2, R0	exptract psw
00002030	5020 8ED8		000010D8	1649+	ST	R2, CCPSW	to save CC
00002034	07FB			1650+	BR	R11	return
00002038				1651+RE43	DC	0F	
00002038				1652+	DROP	R5	
00002038	80000000 00000000			1653	DC	XL08' 8000000000000000'	R1 result
00002040	00000000 00009223			1654	DC	XL16' 0000000000009223372036854775808D'	V1 source
00002048	37203685 4775808D						
00002050				1655			
00002050				1656	VRR_I	VCVBG, 11, 0	ULONG_MAX
00002050		00002050		1657+	DS	0FD	
00002050	0000206C			1658+	USING	*, R5	base for test data and test routine
00002054	002C			1659+T44	DC	A(X44)	address of test routine
00002056	00			1660+	DC	H' 44'	test number
00002057	0B			1661+	DC	XL1' 00'	
00002058	00			1662+	DC	HL1' 11'	&MB
00002059	07			1663+	DC	HL1' 0'	cc
0000205A	E5C3E5C2 C7404040			1664+	DC	HL1' 7'	cc failed mask
00002064	00000010			1665+	DC	CL8' VCVBG'	instruction name
00002068	00002090			1666+	DC	A(16)	result length
				1667+REA44	DC	A(RE44)	result address
				1668+*			INSTRUCTION UNDER TEST ROUTINE
0000206C				1669+X44	DS	0F	
0000206C	E310 8EE8 0004		000010E8	1670+	LG	R1, R1FUDGE	pollute R1
00002072	E710 5048 0006		00002098	1671+	VL	V1, RE44+8	get V1 source
00002078	E611 00B0 0052			1672+	VCVBG	R1, V1, 11	test instruction
0000207E	E310 8F20 0024		00001120	1673+	STG	R1, R10UTPUT	save
00002084	B98D 0020			1674+	EPSW	R2, R0	exptract psw
00002088	5020 8ED8		000010D8	1675+	ST	R2, CCPSW	to save CC
0000208C	07FB			1676+	BR	R11	return
00002090				1677+RE44	DC	0F	
00002090				1678+	DROP	R5	
00002090	FFFFFFFF FFFFFFFF			1679	DC	XL08' FFFFFFFFFFFFFFFFFF'	R1 result
00002098	00000000 00018446			1680	DC	XL16' 0000000000018446744073709551615C'	V1 source
000020A0	74407370 9551615C						
000020A8				1681			
000020A8				1682	VRR_I	VCVBG, 11, 3	ULONG_MAX +1
000020A8		000020A8		1683+	DS	0FD	
000020A8	000020C4			1684+	USING	*, R5	base for test data and test routine
000020AC	002D			1685+T45	DC	A(X45)	address of test routine
000020AE	00			1686+	DC	H' 45'	test number
000020AF	0B			1687+	DC	XL1' 00'	
000020B0	03			1688+	DC	HL1' 11'	&MB
000020B1	0E			1689+	DC	HL1' 3'	cc
000020B2	E5C3E5C2 C7404040			1690+	DC	HL1' 14'	cc failed mask
000020BC	00000010			1691+	DC	CL8' VCVBG'	instruction name
000020C0	000020E8			1692+	DC	A(16)	result length
				1693+REA45	DC	A(RE45)	result address
				1694+*			INSTRUCTION UNDER TEST ROUTINE
000020C4				1695+X45	DS	0F	
000020C4	E310 8EE8 0004		000010E8	1696+	LG	R1, R1FUDGE	pollute R1
000020CA	E710 5048 0006		000020F0	1697+	VL	V1, RE45+8	get V1 source
000020D0	E611 00B0 0052			1698+	VCVBG	R1, V1, 11	test instruction



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000020D6	E310 8F20 0024		00001120	1699+	STG	R1, R10OUTPUT	save
000020DC	B98D 0020			1700+	EPSW	R2, R0	exptract psw
000020E0	5020 8ED8		000010D8	1701+	ST	R2, CCPSW	to save CC
000020E4	07FB			1702+	BR	R11	return
000020E8				1703+RE45	DC	OF	
000020E8				1704+	DROP	R5	
000020E8	00000000 00000000			1705	DC	XL08' 000000000000000000'	R1 result
000020F0	00000000 00018446			1706	DC	XL16' 00000000000018446744073709551616C'	V1 source
000020F8	74407370 9551616C						
				1707			
				1708	VRR_I	VCVBG, 11, 3	ULONG_MAX +11
00002100				1709+	DS	OFD	
00002100		00002100		1710+	USING	*, R5	base for test data and test routine
00002100	0000211C			1711+T46	DC	A(X46)	address of test routine
00002104	002E			1712+	DC	H' 46'	test number
00002106	00			1713+	DC	XL1' 00'	
00002107	0B			1714+	DC	HL1' 11'	&MB
00002108	03			1715+	DC	HL1' 3'	cc
00002109	0E			1716+	DC	HL1' 14'	cc failed mask
0000210A	E5C3E5C2 C7404040			1717+	DC	CL8' VCVBG'	instruction name
00002114	00000010			1718+	DC	A(16)	result length
00002118	00002140			1719+REA46	DC	A(RE46)	result address
				1720+*			INSTRUCTION UNDER TEST ROUTINE
0000211C				1721+X46	DS	OF	
0000211C	E310 8EE8 0004		000010E8	1722+	LG	R1, R1FUDGE	pollute R1
00002122	E710 5048 0006		00002148	1723+	VL	V1, RE46+8	get V1 source
00002128	E611 00B0 0052			1724+	VCVBG	R1, V1, 11	test instruction
0000212E	E310 8F20 0024		00001120	1725+	STG	R1, R10OUTPUT	save
00002134	B98D 0020			1726+	EPSW	R2, R0	exptract psw
00002138	5020 8ED8		000010D8	1727+	ST	R2, CCPSW	to save CC
0000213C	07FB			1728+	BR	R11	return
00002140				1729+RE46	DC	OF	
00002140				1730+	DROP	R5	
00002140	00000000 0000000A			1731	DC	XL08' 0000000000000000A'	R1 result
00002148	00000000 00018446			1732	DC	XL16' 00000000000018446744073709551626C'	V1 source
00002150	74407370 9551626C						
				1733			
00002158	00000000			1734	DC	F' 0'	END OF TABLE
0000215C	00000000			1735	DC	F' 0'	
				1736 *			
				1737 *	table of pointers to individual load test		
				1738 *			
00002160				1739 E6TESTS	DS	OF	
				1740	PTTABLE		
00002160				1741+TTABLE	DS	OF	
00002160	00001188			1742+	DC	A(T1)	address of test
00002164	000011E0			1743+	DC	A(T2)	address of test
00002168	00001238			1744+	DC	A(T3)	address of test
0000216C	00001290			1745+	DC	A(T4)	address of test
00002170	000012E8			1746+	DC	A(T5)	address of test
00002174	00001340			1747+	DC	A(T6)	address of test
00002178	00001398			1748+	DC	A(T7)	address of test
0000217C	000013F0			1749+	DC	A(T8)	address of test
00002180	00001448			1750+	DC	A(T9)	address of test
00002184	000014A0			1751+	DC	A(T10)	address of test
00002188	000014F8			1752+	DC	A(T11)	address of test



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				1795	*****		
				1796	*            Register equates		
				1797	*****		
		00000000	00000001	1799 R0	EQU	0	
		00000001	00000001	1800 R1	EQU	1	
		00000002	00000001	1801 R2	EQU	2	
		00000003	00000001	1802 R3	EQU	3	
		00000004	00000001	1803 R4	EQU	4	
		00000005	00000001	1804 R5	EQU	5	
		00000006	00000001	1805 R6	EQU	6	
		00000007	00000001	1806 R7	EQU	7	
		00000008	00000001	1807 R8	EQU	8	
		00000009	00000001	1808 R9	EQU	9	
		0000000A	00000001	1809 R10	EQU	10	
		0000000B	00000001	1810 R11	EQU	11	
		0000000C	00000001	1811 R12	EQU	12	
		0000000D	00000001	1812 R13	EQU	13	
		0000000E	00000001	1813 R14	EQU	14	
		0000000F	00000001	1814 R15	EQU	15	
				1816	*****		
				1817	*            Register equates		
				1818	*****		
		00000000	00000001	1820 V0	EQU	0	
		00000001	00000001	1821 V1	EQU	1	
		00000002	00000001	1822 V2	EQU	2	
		00000003	00000001	1823 V3	EQU	3	
		00000004	00000001	1824 V4	EQU	4	
		00000005	00000001	1825 V5	EQU	5	
		00000006	00000001	1826 V6	EQU	6	
		00000007	00000001	1827 V7	EQU	7	
		00000008	00000001	1828 V8	EQU	8	
		00000009	00000001	1829 V9	EQU	9	
		0000000A	00000001	1830 V10	EQU	10	
		0000000B	00000001	1831 V11	EQU	11	
		0000000C	00000001	1832 V12	EQU	12	
		0000000D	00000001	1833 V13	EQU	13	
		0000000E	00000001	1834 V14	EQU	14	
		0000000F	00000001	1835 V15	EQU	15	
		00000010	00000001	1836 V16	EQU	16	
		00000011	00000001	1837 V17	EQU	17	
		00000012	00000001	1838 V18	EQU	18	
		00000013	00000001	1839 V19	EQU	19	
		00000014	00000001	1840 V20	EQU	20	
		00000015	00000001	1841 V21	EQU	21	



ASMA Ver. 0.7.0 zvector-e6-11-convertbinary (Zvector E6 VRR-i)																	07 Jun 2024 11:17:36				Page	41
SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES																	
BEGIN	I	00000200	2	91	57	88	89															
CC	U	00000008	1	419	169																	
CCFOUND	X	000010E0	1	391	156	176																
CCMASK	U	00000009	1	420	127																	
CCMSG	U	00000270	1	145	139																	
CCPRTEXP	C	0000108A	1	371	173																	
CCPRTGOT	C	0000109A	1	374	180																	
CCPRTLNE	C	00001047	16	366	376	183																
CCPRTLNG	U	00000055	1	376	182																	
CCPRTNAME	C	00001074	8	369	166																	
CCPRTNUM	C	00001057	3	367	164																	
CCPSW	F	000010D8	4	390	153	551	577	603	629	655	681	707	733	759	786	812	838					
					864	890	916	942	968	994	1024	1050	1076	1102	1128	1154	1180					
					1206	1232	1258	1284	1310	1336	1362	1389	1415	1441	1467	1493	1519					
					1545	1571	1597	1623	1649	1675	1701	1727										
CTLRO	F	00000484	4	312	101	102	103	104														
DECNUM	C	000010C8	16	386	161	163	170	172	177	179	195	197	204	206								
E6TADR	A	0000048C	4	315	110																	
E6TEST	4	00000000	28	414	119																	
E6TESTS	F	00002160	4	1739	315																	
EDIT	X	0000109C	18	381	162	171	178	196	205													
ENDTEST	U	0000035A	1	226	115																	
EOJ	I	00000468	4	302	229																	
EOJPSW	D	00000458	8	300	302																	
FAILCONT	U	0000034A	1	216	186																	
FAILED	F	00001000	4	342	218	227																
FAILMSG	U	00000300	1	193	134																	
FAILPSW	D	00000470	8	304	306																	
FAILTEST	I	00000480	4	306	230																	
IMAGE	1	00000000	8744	0																		
K	U	00000400	1	325	326	327	328															
K64	U	00010000	1	327																		
MB	U	00000007	1	418	147	203																
MB	U	00100000	1	328																		
MSG	I	000003A0	4	262	245																	
MSGCMD	C	000003EE	9	292	275	276																
MSGMSG	C	000003F7	95	293	269	290	267															
MSGMVC	I	000003E8	6	290	273																	
MSGOK	I	000003B6	2	271	268																	
MSGRET	I	000003D6	4	286	279	282																
MSGSAVE	F	000003DC	4	289	265	286																
NEXTE6	U	0000022A	1	112	137	221																
OPNAME	C	0000000A	8	422	166	200																
PAGE	U	00001000	1	326																		
PRT3	C	000010B2	18	384	162	163	164	171	172	173	178	179	180	196	197	198	205					
					206	207																
PRTLNE	C	00001008	16	351	358	210																
PRTLNG	U	0000003F	1	358	209																	
PRTM3	C	00001044	2	356	207																	
PRTNAME	C	00001033	8	354	200																	
PRTNUM	C	00001018	3	352	198																	
RO	U	00000000	1	1799	51	101	104	117	121	122	182	209	217	218	244	246	262					
					265	267	269	271	286	550	576	602	628	654	680	706	732					
					758	785	811	837	863	889	915	941	967	993	1023	1049	1075					
					1101	1127	1153	1179	1205	1231	1257	1283	1309	1335	1361	1388	1414					
					1440	1466	1492	1518	1544	1570	1596	1622	1648	1674	1700	1726						





SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
RE13	F	000015E8	4	866	856    860
RE14	F	00001640	4	892	882    886
RE15	F	00001698	4	918	908    912
RE16	F	000016F0	4	944	934    938
RE17	F	00001748	4	970	960    964
RE18	F	000017A0	4	996	986    990
RE19	F	000017F8	4	1026	1016    1020
RE2	F	00001220	4	579	569    573
RE20	F	00001850	4	1052	1042    1046
RE21	F	000018A8	4	1078	1068    1072
RE22	F	00001900	4	1104	1094    1098
RE23	F	00001958	4	1130	1120    1124
RE24	F	000019B0	4	1156	1146    1150
RE25	F	00001A08	4	1182	1172    1176
RE26	F	00001A60	4	1208	1198    1202
RE27	F	00001AB8	4	1234	1224    1228
RE28	F	00001B10	4	1260	1250    1254
RE29	F	00001B68	4	1286	1276    1280
RE3	F	00001278	4	605	595    599
RE30	F	00001BC0	4	1312	1302    1306
RE31	F	00001C18	4	1338	1328    1332
RE32	F	00001C70	4	1364	1354    1358
RE33	F	00001CC8	4	1391	1381    1385
RE34	F	00001D20	4	1417	1407    1411
RE35	F	00001D78	4	1443	1433    1437
RE36	F	00001DD0	4	1469	1459    1463
RE37	F	00001E28	4	1495	1485    1489
RE38	F	00001E80	4	1521	1511    1515
RE39	F	00001ED8	4	1547	1537    1541
RE4	F	000012D0	4	631	621    625
RE40	F	00001F30	4	1573	1563    1567
RE41	F	00001F88	4	1599	1589    1593
RE42	F	00001FE0	4	1625	1615    1619
RE43	F	00002038	4	1651	1641    1645
RE44	F	00002090	4	1677	1667    1671
RE45	F	000020E8	4	1703	1693    1697
RE46	F	00002140	4	1729	1719    1723
RE5	F	00001328	4	657	647    651
RE6	F	00001380	4	683	673    677
RE7	F	000013D8	4	709	699    703
RE8	F	00001430	4	735	725    729
RE9	F	00001488	4	761	751    755
REA1	A	000011A0	4	543	
REA10	A	000014B8	4	778	
REA11	A	00001510	4	804	
REA12	A	00001568	4	830	
REA13	A	000015C0	4	856	
REA14	A	00001618	4	882	
REA15	A	00001670	4	908	
REA16	A	000016C8	4	934	
REA17	A	00001720	4	960	
REA18	A	00001778	4	986	
REA19	A	000017D0	4	1016	
REA2	A	000011F8	4	569	
REA20	A	00001828	4	1042	
REA21	A	00001880	4	1068	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES	
REA22	A	000018D8	4	1094		
REA23	A	00001930	4	1120		
REA24	A	00001988	4	1146		
REA25	A	000019E0	4	1172		
REA26	A	00001A38	4	1198		
REA27	A	00001A90	4	1224		
REA28	A	00001AE8	4	1250		
REA29	A	00001B40	4	1276		
REA3	A	00001250	4	595		
REA30	A	00001B98	4	1302		
REA31	A	00001BF0	4	1328		
REA32	A	00001C48	4	1354		
REA33	A	00001CA0	4	1381		
REA34	A	00001CF8	4	1407		
REA35	A	00001D50	4	1433		
REA36	A	00001DA8	4	1459		
REA37	A	00001E00	4	1485		
REA38	A	00001E58	4	1511		
REA39	A	00001EB0	4	1537		
REA4	A	000012A8	4	621		
REA40	A	00001F08	4	1563		
REA41	A	00001F60	4	1589		
REA42	A	00001FB8	4	1615		
REA43	A	00002010	4	1641		
REA44	A	00002068	4	1667		
REA45	A	000020C0	4	1693		
REA46	A	00002118	4	1719		
REA5	A	00001300	4	647		
REA6	A	00001358	4	673		
REA7	A	000013B0	4	699		
REA8	A	00001408	4	725		
REA9	A	00001460	4	751		
READDR	A	00000018	4	425	132	
REG2LOW	U	000000DD	1	332		
REG2PATT	U	AABBCCDD	1	331		
RELEN	A	00000014	4	424		
RPTDWSAV	D	00000390	8	255	244	246
RPTERROR	I	00000368	4	239	184	211
RPTSAVE	F	00000388	4	252	239	249
RPTSVR5	F	0000038C	4	253	240	248
SVOLDPSW	U	00000140	0	53		
T1	A	00001188	4	535	1742	
T10	A	000014A0	4	770	1751	
T11	A	000014F8	4	796	1752	
T12	A	00001550	4	822	1753	
T13	A	000015A8	4	848	1754	
T14	A	00001600	4	874	1755	
T15	A	00001658	4	900	1756	
T16	A	000016B0	4	926	1757	
T17	A	00001708	4	952	1758	
T18	A	00001760	4	978	1759	
T19	A	000017B8	4	1008	1760	
T2	A	000011E0	4	561	1743	
T20	A	00001810	4	1034	1761	
T21	A	00001868	4	1060	1762	
T22	A	000018C0	4	1086	1763	





SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
V1FUDGE	X	00001138	16	403	
V1FUDGEB	X	00001148	16	404	
V1INPUT	C	00001158	16	405	
V10OUTPUT	X	00001100	16	399	
V2	U	00000002	1	1822	
V20	U	00000014	1	1840	
V21	U	00000015	1	1841	
V22	U	00000016	1	1842	
V23	U	00000017	1	1843	
V24	U	00000018	1	1844	
V25	U	00000019	1	1845	
V26	U	0000001A	1	1846	
V27	U	0000001B	1	1847	
V28	U	0000001C	1	1848	
V29	U	0000001D	1	1849	
V3	U	00000003	1	1823	
V30	U	0000001E	1	1850	
V31	U	0000001F	1	1851	
V4	U	00000004	1	1824	
V5	U	00000005	1	1825	
V6	U	00000006	1	1826	
V7	U	00000007	1	1827	
V8	U	00000008	1	1828	
V9	U	00000009	1	1829	
X1	F	000011A4	4	545	535
X10	F	000014BC	4	780	770
X11	F	00001514	4	806	796
X12	F	0000156C	4	832	822
X13	F	000015C4	4	858	848
X14	F	0000161C	4	884	874
X15	F	00001674	4	910	900
X16	F	000016CC	4	936	926
X17	F	00001724	4	962	952
X18	F	0000177C	4	988	978
X19	F	000017D4	4	1018	1008
X2	F	000011FC	4	571	561
X20	F	0000182C	4	1044	1034
X21	F	00001884	4	1070	1060
X22	F	000018DC	4	1096	1086
X23	F	00001934	4	1122	1112
X24	F	0000198C	4	1148	1138
X25	F	000019E4	4	1174	1164
X26	F	00001A3C	4	1200	1190
X27	F	00001A94	4	1226	1216
X28	F	00001AEC	4	1252	1242
X29	F	00001B44	4	1278	1268
X3	F	00001254	4	597	587
X30	F	00001B9C	4	1304	1294
X31	F	00001BF4	4	1330	1320
X32	F	00001C4C	4	1356	1346
X33	F	00001CA4	4	1383	1373
X34	F	00001CFC	4	1409	1399
X35	F	00001D54	4	1435	1425
X36	F	00001DAC	4	1461	1451
X37	F	00001E04	4	1487	1477
X38	F	00001E5C	4	1513	1503





DESC	SYMBOL	SIZE	POS	ADDR
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**Entry: 0**

Image	IMAGE	8744	0000- 2227	0000- 2227
Regi on		8744	0000- 2227	0000- 2227
CSECT	ZVE6TST	8744	0000- 2227	0000- 2227



**STMT**

**FILE NAME**

```
1 /home/tn529/sharedvfp/tests/zvector-e6-11-convertbinary.asm
```

**\*\* NO ERRORS FOUND \*\***